

----- Group:265 Sn.26553 personal preparations -----

## Vampset: CT&VT settings + output matrix

### Test State:

Command executed

Test passed

### Test Module

Name:	OMICRON ExeCute	Version:	3.00 SR 2
Test Start:	05-joulu-2014 17:13:31	Test End:	05-joulu-2014 17:16:19
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

----- Group end:265 Sn.26553 personal preparations -----

## Hardware Configuration

### Test Equipment

Type	Serial Number
CMC356	DF980F

### Hardware Check

Performed At	Result	Details
3.10.2014 10:29:17	Passed	

----- Group:Circuit breaker failure protection CBFP (50BF) -----

----- Group:Motor mode -----

----- Group:CT 5A (265) -----

## Test Object - Device Settings

### Substation/Bay:

Substation:  
Bay:

Substation address:  
Bay address:

**Device:**

Name/description: CT="1A"  
 Device type:  
 Serial/model number:  
 Additional info 1:  
 Additional info 2:

Manufacturer:  
 Device address:

**Vampset: Disable stages****Test State:**

Command executed  
 Test passed

**Test Module**

Name: OMICRON ExeCute  
 Test Start: 05-joulu-2014 17:17:36  
 User Name: Jesse Saastamoinen  
 Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
 Test End: 05-joulu-2014 17:17:52  
 Manager:

**Vampset: 50BF****Test State:**

Command executed  
 Test passed

**Test Module**

Name: OMICRON ExeCute  
 Test Start: 05-joulu-2014 17:19:08  
 User Name: Jesse Saastamoinen  
 Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
 Test End: 05-joulu-2014 17:20:49  
 Manager:

**CBFP check Operation delay=min.:****Test Settings**

State	Normal situation	Pick-up (I>)	Release	Pick-up (I>) #2	Fault disappears (No CBFP trip)	Cold boot #1	No trip after boot
I 1	700,0 mA 0,00 ° 50,000 Hz	840,0 mA 0,00 ° 50,000 Hz	700,0 mA 0,00 ° 50,000 Hz	840,0 mA 0,00 ° 50,000 Hz	700,0 mA 0,00 ° 50,000 Hz	700,0 mA 0,00 ° 50,000 Hz	700,0 mA 0,00 ° 50,000 Hz
I 2	700,0 mA -120,00 ° 50,000 Hz	840,0 mA -120,00 ° 50,000 Hz	700,0 mA -120,00 ° 50,000 Hz	840,0 mA -120,00 ° 50,000 Hz	700,0 mA -120,00 ° 50,000 Hz	700,0 mA -120,00 ° 50,000 Hz	700,0 mA -120,00 ° 50,000 Hz
I 3	700,0 mA 120,00 ° 50,000 Hz	840,0 mA 120,00 ° 50,000 Hz	700,0 mA 120,00 ° 50,000 Hz	840,0 mA 120,00 ° 50,000 Hz	700,0 mA 120,00 ° 50,000 Hz	700,0 mA 120,00 ° 50,000 Hz	700,0 mA 120,00 ° 50,000 Hz

**Test Module**

Name: OMICRON State Sequencer  
 Test Start: 05-joulu-2014 17:22:09  
 User Name: Jesse Saastamoinen  
 Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
 Test End: 05-joulu-2014 17:22:09  
 Manager:

**Test Results**

## Time Assessment

Name	Ignore before	Start	Stop	Tnom	Tdev-	Tdev+	Tact	Tdev	Assess
CBFP trip	Pick-up (I>)	Trip (T1) 0>1	Power swing 0>1	100,0 ms	18,00 ms	18,00 ms	102,1 ms	2,100 ms	+
CBFP release	Release	Trip (T1) 1>0	Power swing 1>0	95,00 ms	95,00 ms	0,000 s	70,30 ms	-24,70 ms	+
I> trip	Pick-up (I>) #2	Pick-up (I>) #2	Trip (T1) 0>1	1,000 s	30,00 ms	30,00 ms	998,1 ms	-1,900 ms	+

Assess: + .. Passed x .. Failed o .. Not assessed

## State Assessment

	Normal situation	Pick-up (I>)	Release	Pick-up (I>) #2	Fault disappears (No CBFP trip)	Cold boot #1	No trip after boot
Assess	+	+	+	+	+	+	+
Tolerance	0,000 s	1,150 s	190,0 ms	1,030 s	0,000 s	0,000 s	0,000 s
Power swing	0	1	0	0	0	0	0
Start (A1)	0	1	0	1	X	0	0
Trip (T1)	0	1	0	1	X	0	0

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:  
Test passed

-----Group end:CT 5A (265)-----

-----Group end:Motor mode-----

-----Group end:Circuit breaker failure protection CBFP (50BF)-----

-----Group:Transformer differential stage DI> and DI>> (87)-----

-----Group:Pri/Sec = 5A/5A-----

## Test Object - Device Settings

### Substation/Bay:

Substation:  
Bay:

Substation address:  
Bay address:

### Device:

Name/description: CT="1A", CT'="1A"  
Device type:  
Serial/model number:  
Additional info 1:  
Additional info 2:

Manufacturer:  
Device address:

## Vampset: Disable stages

Test State:  
Command executed  
Test passed

## Test Module

Name: OMICRON ExeCute  
Test Start: 05-joulu-2014 17:23:25

Version:  
Test End:

3.00 SR 2  
05-joulu-2014 17:23:46

User Name: Jesse Saastamoinen  
Company: Schneider Electric - Vamp

Manager:

## Vampset: 87

Test State:  
Command executed  
Test passed

### Test Module

Name: OMICRON ExeCute Version: 3.00 SR 2  
Test Start: 05-joulu-2014 17:25:02 Test End: 05-joulu-2014 17:25:49  
User Name: Jesse Saastamoinen Manager:  
Company: Schneider Electric - Vamp

Curve check DI>=min,Slope1=min,Bias=min,Slope2=min,DI>>=min

### Test Module

Name: OMICRON Diff Operating Version: 3.00 SR 2  
Characteristic  
Test Start: 05-joulu-2014 17:27:08 Test End: 05-joulu-2014 17:27:09  
User Name: Jesse Saastamoinen Manager:  
Company: Schneider Electric - Vamp

### Test Results for Fault Type L3-L1 at Reference Side Primary

Idiff	Ibias	Nominal Trip Time	Actual Trip Time	State	Result
0,04 In	0,33 In	N/T	N/T	Tested	Passed
0,05 In	0,74 In	N/T	N/T	Tested	Passed
0,39 In	1,66 In	N/T	N/T	Tested	Passed
4,87 In	10,84 In	N/T	N/T	Tested	Passed
5,13 In	11,60 In	0,0200 s	0,0479 s	Tested	Passed
0,41 In	1,66 In	0,0400 s	0,0457 s	Tested	Passed
0,07 In	0,74 In	0,0400 s	0,0560 s	Tested	Passed
0,06 In	0,33 In	0,0400 s	0,0551 s	Tested	Passed

Test State:  
Test passed  
8 out of 8 points tested.  
8 points passed.  
0 points failed.

### Operation time DI> (1.2xIset):

### Test Settings

State	Normal situation	Pick-up DI> (IL1-IL2-IL3)	Drop-off	Pick-up DI> (IL1-IL2-IL3) #2	Drop-off #2	Pick-up DI> (IL1-IL2-IL3) #3	Drop-off #3	Pick-up DI> (IL1-IL2-IL3) #4
I 1	0,000 A 0,00 ° 50,000 Hz	2,379 A 0,00 ° 50,000 Hz	0,000 A 0,00 ° 50,000 Hz	2,379 A 0,00 ° 50,000 Hz	0,000 A 0,00 ° 50,000 Hz	2,379 A 0,00 ° 50,000 Hz	0,000 A 0,00 ° 50,000 Hz	2,379 A 0,00 ° 50,000 Hz
I 2	0,000 A -120,00 ° 50,000 Hz	2,379 A -120,00 ° 50,000 Hz	0,000 A -120,00 ° 50,000 Hz	2,379 A -120,00 ° 50,000 Hz	0,000 A -120,00 ° 50,000 Hz	2,379 A -120,00 ° 50,000 Hz	0,000 A -120,00 ° 50,000 Hz	2,379 A -120,00 ° 50,000 Hz
I 3	0,000 A 120,00 ° 50,000 Hz	2,379 A 120,00 ° 50,000 Hz	0,000 A 120,00 ° 50,000 Hz	2,379 A 120,00 ° 50,000 Hz	0,000 A 120,00 ° 50,000 Hz	2,379 A 120,00 ° 50,000 Hz	0,000 A 120,00 ° 50,000 Hz	2,379 A 120,00 ° 50,000 Hz
I1'	0,000 A 0,00 ° 50,000 Hz	2,117 A 0,00 ° 50,000 Hz	0,000 A 0,00 ° 50,000 Hz	2,117 A 0,00 ° 50,000 Hz	0,000 A 0,00 ° 50,000 Hz	2,117 A 0,00 ° 50,000 Hz	0,000 A 0,00 ° 50,000 Hz	2,117 A 0,00 ° 50,000 Hz

[illegible]

I1'	0,000 A 0,00 ° 50,000 Hz	0,000 A 0,00 ° 50,000 Hz	0,000 A 0,00 ° 50,000 Hz	0,000 A 0,00 ° 50,000 Hz	0,000 A 0,00 ° 50,000 Hz	0,000 A 0,00 ° 50,000 Hz	0,000 A 0,00 ° 50,000 Hz	962,0 mA 0,00 ° 50,000 Hz
I2'	0,000 A -120,00 ° 50,000 Hz	2,117 A 0,00 ° 50,000 Hz	0,000 A -120,00 ° 50,000 Hz	2,117 A 0,00 ° 50,000 Hz	0,000 A -120,00 ° 50,000 Hz	2,117 A 0,00 ° 50,000 Hz	0,000 A -120,00 ° 50,000 Hz	962,0 mA -120,00 ° 50,000 Hz
I3'	0,000 A 120,00 ° 50,000 Hz	2,117 A 180,00 ° 50,000 Hz	0,000 A 120,00 ° 50,000 Hz	2,117 A 180,00 ° 50,000 Hz	0,000 A 120,00 ° 50,000 Hz	2,117 A 180,00 ° 50,000 Hz	0,000 A 120,00 ° 50,000 Hz	962,0 mA 120,00 ° 50,000 Hz
State	No trip after boot (Grp1)							
I 1	700,0 mA 0,00 ° 50,000 Hz							
I 2	700,0 mA -120,00 ° 50,000 Hz							
I 3	700,0 mA 120,00 ° 50,000 Hz							
I1'	962,0 mA 0,00 ° 50,000 Hz							
I2'	962,0 mA -120,00 ° 50,000 Hz							
I3'	962,0 mA 120,00 ° 50,000 Hz							

## Test Module

Name: OMICRON State Sequencer  
Test Start: 05-joulu-2014 17:28:31  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - Vamp

Version:  
Test End:  
Manager:

3.00 SR 2  
05-joulu-2014 17:28:32

## Test Results

## Time Assessment

Name	Ignore before	Start	Stop	Tnom	Tdev-	Tdev+	Tact	Tdev	Assess
DI> trip (IL1-IL2-IL3) #1	Pick-up DI> (IL1-IL2-IL3)	Pick-up DI> (IL1-IL2-IL3)	Trip (T1) 0>1	60,00 ms	60,00 ms	0,000 s	38,90 ms	-21,10 ms	+
DI> trip (IL1-IL2-IL3) #2	Pick-up DI> (IL1-IL2-IL3) #2	Pick-up DI> (IL1-IL2-IL3) #2	Trip (T1) 0>1	60,00 ms	60,00 ms	0,000 s	40,20 ms	-19,80 ms	+
DI> trip (IL1-IL2-IL3) #3	Pick-up DI> (IL1-IL2-IL3) #3	Pick-up DI> (IL1-IL2-IL3) #3	Trip (T1) 0>1	60,00 ms	60,00 ms	0,000 s	39,90 ms	-20,10 ms	+
DI> trip (IL1-IL2-IL3) #4	Pick-up DI> (IL1-IL2-IL3) #4	Pick-up DI> (IL1-IL2-IL3) #4	Trip (T1) 0>1	60,00 ms	60,00 ms	0,000 s	40,10 ms	-19,90 ms	+
DI> trip (IL1-IL2-IL3) #5	Pick-up DI> (IL1-IL2-IL3) #5	Pick-up DI> (IL1-IL2-IL3) #5	Trip (T1) 0>1	60,00 ms	60,00 ms	0,000 s	39,90 ms	-20,10 ms	+
DI> trip (IL3-N) #1	Pick-up DI> (IL3-N)	Pick-up DI> (IL3-N)	Trip (T1) 0>1	60,00 ms	60,00 ms	0,000 s	40,10 ms	-19,90 ms	+
DI> trip (IL3-N) #2	Pick-up DI> (IL3-N) #2	Pick-up DI> (IL3-N) #2	Trip (T1) 0>1	60,00 ms	60,00 ms	0,000 s	40,10 ms	-19,90 ms	+
DI> trip (IL3-N) #3	Pick-up DI> (IL3-N) #3	Pick-up DI> (IL3-N) #3	Trip (T1) 0>1	60,00 ms	60,00 ms	0,000 s	40,00 ms	-20,00 ms	+
DI> trip (IL3-N) #4	Pick-up DI> (IL3-N) #4	Pick-up DI> (IL3-N) #4	Trip (T1) 0>1	60,00 ms	60,00 ms	0,000 s	40,00 ms	-20,00 ms	+
DI> trip (IL3-N) #5	Pick-up DI> (IL3-N) #5	Pick-up DI> (IL3-N) #5	Trip (T1) 0>1	60,00 ms	60,00 ms	0,000 s	40,20 ms	-19,80 ms	+
DI> trip (IL2-IL3) #1	Pick-up DI> (IL2-IL3)	Pick-up DI> (IL2-IL3)	Trip (T1) 0>1	60,00 ms	60,00 ms	0,000 s	39,80 ms	-20,20 ms	+
DI> trip (IL2-IL3) #2	Pick-up DI> (IL2-IL3) #2	Pick-up DI> (IL2-IL3) #2	Trip (T1) 0>1	60,00 ms	60,00 ms	0,000 s	40,10 ms	-19,90 ms	+
DI> trip (IL2-IL3) #3	Pick-up DI> (IL2-IL3) #3	Pick-up DI> (IL2-IL3) #3	Trip (T1) 0>1	60,00 ms	60,00 ms	0,000 s	40,00 ms	-20,00 ms	+
DI> trip (IL2-IL3) #4	Pick-up DI> (IL2-IL3) #4	Pick-up DI> (IL2-IL3) #4	Trip (T1) 0>1	60,00 ms	60,00 ms	0,000 s	40,20 ms	-19,80 ms	+
DI> trip (IL2-IL3) #5	Pick-up DI> (IL2-IL3) #5	Pick-up DI> (IL2-IL3) #5	Trip (T1) 0>1	60,00 ms	60,00 ms	0,000 s	39,90 ms	-20,10 ms	+

Assess: + .. Passed x .. Failed o .. Not assessed

## State Assessment

	Normal situation	Pick-up DI> (IL1-IL2-IL3)	Drop-off	Pick-up DI> (IL1-IL2-IL3) #2	Drop-off #2	Pick-up DI> (IL1-IL2-IL3) #3	Drop-off #3	Pick-up DI> (IL1-IL2-IL3) #4
Assess	+	+	+	+	+	+	+	+
Tolerance	0,000 s	60,00 ms	95,00 ms	60,00 ms	95,00 ms	60,00 ms	95,00 ms	60,00 ms
Trip (T1)	0	1	0	1	0	1	0	1
	Drop-off #4	Pick-up DI> (IL1-IL2-IL3) #5	Drop-off #5	Pick-up DI> (IL3-N)	Drop-off #6	Pick-up DI> (IL3-N) #2	Drop-off #7	Pick-up DI> (IL3-N) #3

<b>Assess</b>	+	+	+	+	+	+	+	+
<b>Tolerance</b>	95,00 ms	60,00 ms	95,00 ms	60,00 ms	95,00 ms	60,00 ms	95,00 ms	60,00 ms
<b>Trip (T1)</b>	0	1	0	1	0	1	0	1
	<b>Drop-off #8</b>	<b>Pick-up DI&gt; (IL3-N) #4</b>	<b>Drop-off #9</b>	<b>Pick-up DI&gt; (IL3-N) #5</b>	<b>Drop-off #10</b>	<b>Pick-up DI&gt; (IL2-IL3)</b>	<b>Drop-off #11</b>	<b>Pick-up DI&gt; (IL2-IL3) #2</b>
<b>Assess</b>	+	+	+	+	+	+	+	+
<b>Tolerance</b>	95,00 ms	60,00 ms	95,00 ms	60,00 ms	95,00 ms	60,00 ms	95,00 ms	60,00 ms
<b>Trip (T1)</b>	0	1	0	1	0	1	0	1
	<b>Drop-off #12</b>	<b>Pick-up DI&gt; (IL2-IL3) #3</b>	<b>Drop-off #13</b>	<b>Pick-up DI&gt; (IL2-IL3) #4</b>	<b>Drop-off #14</b>	<b>Pick-up DI&gt; (IL2-IL3) #5</b>	<b>Drop-off #15</b>	<b>Cold boot #1</b>
<b>Assess</b>	+	+	+	+	+	+	+	+
<b>Tolerance</b>	95,00 ms	60,00 ms	95,00 ms	60,00 ms	95,00 ms	60,00 ms	95,00 ms	0,000 s
<b>Trip (T1)</b>	0	1	0	1	0	1	0	0
	<b>No trip after boot (Grp1)</b>							
<b>Assess</b>	+							
<b>Tolerance</b>	0,000 s							
<b>Trip (T1)</b>	0							

**Test State:**  
**Test passed**

## Test Settings



[illegible]

I3'	0,000 A 120,00 ° 50,000 Hz	1,009 A 180,00 ° 50,000 Hz	0,000 A 120,00 ° 50,000 Hz	1,009 A 180,00 ° 50,000 Hz	0,000 A 120,00 ° 50,000 Hz	1,009 A 180,00 ° 50,000 Hz	0,000 A 120,00 ° 50,000 Hz	962,0 mA 120,00 ° 50,000 Hz
State	No trip after boot (Grp1)							
I 1	700,0 mA 0,00 ° 50,000 Hz							
I 2	700,0 mA -120,00 ° 50,000 Hz							
I 3	700,0 mA 120,00 ° 50,000 Hz							
I1'	962,0 mA 0,00 ° 50,000 Hz							
I2'	962,0 mA -120,00 ° 50,000 Hz							
I3'	962,0 mA 120,00 ° 50,000 Hz							

## Test Module

Name: OMICRON State Sequencer  
 Test Start: 05-joulu-2014 17:29:56  
 User Name: Jesse Saastamoinen  
 Company: Schneider Electric - Vamp

Version:  
 Test End:  
 Manager:

3.00 SR 2  
 05-joulu-2014 17:29:57

## Test Results

## Time Assessment

Name	Ignore before	Start	Stop	Tnom	Tdev-	Tdev+	Tact	Tdev	Assess
DI> trip (IL1-IL2-IL3) #1	Pick-up DI> (IL1-IL2-IL3)	Pick-up DI> (IL1-IL2-IL3)	Trip (T1) 0>1	50,00 ms	50,00 ms	0,000 s	37,10 ms	-12,90 ms	+
DI> trip (IL1-IL2-IL3) #2	Pick-up DI> (IL1-IL2-IL3) #2	Pick-up DI> (IL1-IL2-IL3) #2	Trip (T1) 0>1	50,00 ms	50,00 ms	0,000 s	40,20 ms	-9,800 ms	+
DI> trip (IL1-IL2-IL3) #3	Pick-up DI> (IL1-IL2-IL3) #3	Pick-up DI> (IL1-IL2-IL3) #3	Trip (T1) 0>1	50,00 ms	50,00 ms	0,000 s	40,00 ms	-10,00 ms	+
DI> trip (IL1-IL2-IL3) #4	Pick-up DI> (IL1-IL2-IL3) #4	Pick-up DI> (IL1-IL2-IL3) #4	Trip (T1) 0>1	50,00 ms	50,00 ms	0,000 s	40,10 ms	-9,900 ms	+
DI> trip (IL1-IL2-IL3) #5	Pick-up DI> (IL1-IL2-IL3) #5	Pick-up DI> (IL1-IL2-IL3) #5	Trip (T1) 0>1	50,00 ms	50,00 ms	0,000 s	39,90 ms	-10,10 ms	+
DI> trip (IL3-N) #1	Pick-up DI> (IL3-N)	Pick-up DI> (IL3-N)	Trip (T1) 0>1	50,00 ms	50,00 ms	0,000 s	40,10 ms	-9,900 ms	+
DI> trip (IL3-N) #2	Pick-up DI> (IL3-N) #2	Pick-up DI> (IL3-N) #2	Trip (T1) 0>1	50,00 ms	50,00 ms	0,000 s	40,00 ms	-10,00 ms	+
DI> trip (IL3-N) #3	Pick-up DI> (IL3-N) #3	Pick-up DI> (IL3-N) #3	Trip (T1) 0>1	50,00 ms	50,00 ms	0,000 s	40,00 ms	-10,00 ms	+
DI> trip (IL3-N) #4	Pick-up DI> (IL3-N) #4	Pick-up DI> (IL3-N) #4	Trip (T1) 0>1	50,00 ms	50,00 ms	0,000 s	40,00 ms	-10,00 ms	+
DI> trip (IL3-N) #5	Pick-up DI> (IL3-N) #5	Pick-up DI> (IL3-N) #5	Trip (T1) 0>1	50,00 ms	50,00 ms	0,000 s	40,00 ms	-10,00 ms	+
DI> trip (IL2-IL3) #1	Pick-up DI> (IL2-IL3)	Pick-up DI> (IL2-IL3)	Trip (T1) 0>1	50,00 ms	50,00 ms	0,000 s	40,00 ms	-10,00 ms	+
DI> trip (IL2-IL3) #2	Pick-up DI> (IL2-IL3) #2	Pick-up DI> (IL2-IL3) #2	Trip (T1) 0>1	50,00 ms	50,00 ms	0,000 s	40,20 ms	-9,800 ms	+
DI> trip (IL2-IL3) #3	Pick-up DI> (IL2-IL3) #3	Pick-up DI> (IL2-IL3) #3	Trip (T1) 0>1	50,00 ms	50,00 ms	0,000 s	39,90 ms	-10,10 ms	+
DI> trip (IL2-IL3) #4	Pick-up DI> (IL2-IL3) #4	Pick-up DI> (IL2-IL3) #4	Trip (T1) 0>1	50,00 ms	50,00 ms	0,000 s	40,20 ms	-9,800 ms	+
DI> trip (IL2-IL3) #5	Pick-up DI> (IL2-IL3) #5	Pick-up DI> (IL2-IL3) #5	Trip (T1) 0>1	50,00 ms	50,00 ms	0,000 s	39,90 ms	-10,10 ms	+

Assess: + .. Passed x .. Failed o .. Not assessed

## State Assessment

	Normal situation	Pick-up DI> (IL1-IL2-IL3)	Drop-off	Pick-up DI> (IL1-IL2-IL3) #2	Drop-off #2	Pick-up DI> (IL1-IL2-IL3) #3	Drop-off #3	Pick-up DI> (IL1-IL2-IL3) #4
Assess	+	+	+	+	+	+	+	+
Tolerance	0,000 s	50,00 ms	95,00 ms	50,00 ms	95,00 ms	50,00 ms	95,00 ms	50,00 ms
Trip (T1)	0	1	0	1	0	1	0	1
	Drop-off #4	Pick-up DI> (IL1-IL2-IL3) #5	Drop-off #5	Pick-up DI> (IL3-N)	Drop-off #6	Pick-up DI> (IL3-N) #2	Drop-off #7	Pick-up DI> (IL3-N) #3

<b>Assess</b>	+	+	+	+	+	+	+	+
<b>Tolerance</b>	95,00 ms	50,00 ms	95,00 ms	50,00 ms	95,00 ms	50,00 ms	95,00 ms	50,00 ms
<b>Trip (T1)</b>	0	1	0	1	0	1	0	1
	<b>Drop-off #8</b>	<b>Pick-up DI&gt; (IL3-N) #4</b>	<b>Drop-off #9</b>	<b>Pick-up DI&gt; (IL3-N) #5</b>	<b>Drop-off #10</b>	<b>Pick-up DI&gt; (IL2-IL3)</b>	<b>Drop-off #11</b>	<b>Pick-up DI&gt; (IL2-IL3) #2</b>
<b>Assess</b>	+	+	+	+	+	+	+	+
<b>Tolerance</b>	95,00 ms	50,00 ms	95,00 ms	50,00 ms	95,00 ms	50,00 ms	95,00 ms	50,00 ms
<b>Trip (T1)</b>	0	1	0	1	0	1	0	1
	<b>Drop-off #12</b>	<b>Pick-up DI&gt; (IL2-IL3) #3</b>	<b>Drop-off #13</b>	<b>Pick-up DI&gt; (IL2-IL3) #4</b>	<b>Drop-off #14</b>	<b>Pick-up DI&gt; (IL2-IL3) #5</b>	<b>Drop-off #15</b>	<b>Cold boot #1</b>
<b>Assess</b>	+	+	+	+	+	+	+	+
<b>Tolerance</b>	95,00 ms	50,00 ms	95,00 ms	50,00 ms	95,00 ms	50,00 ms	95,00 ms	0,000 s
<b>Trip (T1)</b>	0	1	0	1	0	1	0	0
	<b>No trip after boot (Grp1)</b>							
<b>Assess</b>	+							
<b>Tolerance</b>	0,000 s							
<b>Trip (T1)</b>	0							

**Test State:**  
**Test passed**

## Test Settings

[illegible]

I3'	0,000 A 120,00 ° 50,000 Hz	241,0 mA 180,00 ° 50,000 Hz	0,000 A 120,00 ° 50,000 Hz	241,0 mA 180,00 ° 50,000 Hz	0,000 A 120,00 ° 50,000 Hz	241,0 mA 180,00 ° 50,000 Hz	0,000 A 120,00 ° 50,000 Hz	962,0 mA 120,00 ° 50,000 Hz
State	No trip after boot (Grp1)							
I 1	700,0 mA 0,00 ° 50,000 Hz							
I 2	700,0 mA -120,00 ° 50,000 Hz							
I 3	700,0 mA 120,00 ° 50,000 Hz							
I1'	962,0 mA 0,00 ° 50,000 Hz							
I2'	962,0 mA -120,00 ° 50,000 Hz							
I3'	962,0 mA 120,00 ° 50,000 Hz							

## Test Module

Name: OMICRON State Sequencer  
 Test Start: 05-joulu-2014 17:31:21  
 User Name: Jesse Saastamoinen  
 Company: Schneider Electric - Vamp

Version:  
 Test End:  
 Manager:

3.00 SR 2  
 05-joulu-2014 17:31:22

## Test Results

## Time Assessment

Name	Ignore before	Start	Stop	Tnom	Tdev-	Tdev+	Tact	Tdev	Assess
DI>> trip (IL1-IL2-IL3) #1	Pick-up DI>> (IL1-IL2-IL3)	Pick-up DI>> (IL1-IL2-IL3)	Trip (T1) 0>1	40,00 ms	40,00 ms	0,000 s	33,60 ms	-6,400 ms	+
DI>> trip (IL1-IL2-IL3) #2	Pick-up DI>> (IL1-IL2-IL3) #2	Pick-up DI>> (IL1-IL2-IL3) #2	Trip (T1) 0>1	40,00 ms	40,00 ms	0,000 s	30,20 ms	-9,800 ms	+
DI>> trip (IL1-IL2-IL3) #3	Pick-up DI>> (IL1-IL2-IL3) #3	Pick-up DI>> (IL1-IL2-IL3) #3	Trip (T1) 0>1	40,00 ms	40,00 ms	0,000 s	30,00 ms	-10,00 ms	+
DI>> trip (IL1-IL2-IL3) #4	Pick-up DI>> (IL1-IL2-IL3) #4	Pick-up DI>> (IL1-IL2-IL3) #4	Trip (T1) 0>1	40,00 ms	40,00 ms	0,000 s	30,00 ms	-10,00 ms	+
DI>> trip (IL1-IL2-IL3) #5	Pick-up DI>> (IL1-IL2-IL3) #5	Pick-up DI>> (IL1-IL2-IL3) #5	Trip (T1) 0>1	40,00 ms	40,00 ms	0,000 s	30,20 ms	-9,800 ms	+
DI>> trip (IL3-N) #1	Pick-up DI>> (IL3-N)	Pick-up DI>> (IL3-N)	Trip (T1) 0>1	40,00 ms	40,00 ms	0,000 s	29,80 ms	-10,20 ms	+
DI>> trip (IL3-N) #2	Pick-up DI>> (IL3-N) #2	Pick-up DI>> (IL3-N) #2	Trip (T1) 0>1	40,00 ms	40,00 ms	0,000 s	30,10 ms	-9,900 ms	+
DI>> trip (IL3-N) #3	Pick-up DI>> (IL3-N) #3	Pick-up DI>> (IL3-N) #3	Trip (T1) 0>1	40,00 ms	40,00 ms	0,000 s	30,20 ms	-9,800 ms	+
DI>> trip (IL3-N) #4	Pick-up DI>> (IL3-N) #4	Pick-up DI>> (IL3-N) #4	Trip (T1) 0>1	40,00 ms	40,00 ms	0,000 s	29,90 ms	-10,10 ms	+
DI>> trip (IL3-N) #5	Pick-up DI>> (IL3-N) #5	Pick-up DI>> (IL3-N) #5	Trip (T1) 0>1	40,00 ms	40,00 ms	0,000 s	30,00 ms	-10,00 ms	+
DI>> trip (IL2-IL3) #1	Pick-up DI>> (IL2-IL3)	Pick-up DI>> (IL2-IL3)	Trip (T1) 0>1	40,00 ms	40,00 ms	0,000 s	30,10 ms	-9,900 ms	+
DI>> trip (IL2-IL3) #2	Pick-up DI>> (IL2-IL3) #2	Pick-up DI>> (IL2-IL3) #2	Trip (T1) 0>1	40,00 ms	40,00 ms	0,000 s	29,90 ms	-10,10 ms	+
DI>> trip (IL2-IL3) #3	Pick-up DI>> (IL2-IL3) #3	Pick-up DI>> (IL2-IL3) #3	Trip (T1) 0>1	40,00 ms	40,00 ms	0,000 s	30,00 ms	-10,00 ms	+
DI>> trip (IL2-IL3) #4	Pick-up DI>> (IL2-IL3) #4	Pick-up DI>> (IL2-IL3) #4	Trip (T1) 0>1	40,00 ms	40,00 ms	0,000 s	30,00 ms	-10,00 ms	+
DI>> trip (IL2-IL3) #5	Pick-up DI>> (IL2-IL3) #5	Pick-up DI>> (IL2-IL3) #5	Trip (T1) 0>1	40,00 ms	40,00 ms	0,000 s	30,20 ms	-9,800 ms	+

Assess: + .. Passed x .. Failed o .. Not assessed

## State Assessment

	Normal situation	Pick-up DI>> (IL1-IL2-IL3)	Drop-off	Pick-up DI>> (IL1-IL2-IL3) #2	Drop-off #2	Pick-up DI>> (IL1-IL2-IL3) #3	Drop-off #3	Pick-up DI>> (IL1-IL2-IL3) #4
Assess	+	+	+	+	+	+	+	+
Tolerance	0,000 s	40,00 ms	95,00 ms	40,00 ms	95,00 ms	40,00 ms	95,00 ms	40,00 ms
Trip (T1)	0	1	0	1	0	1	0	1
	Drop-off #4	Pick-up DI>> (IL1-IL2-IL3) #5	Drop-off #5	Pick-up DI>> (IL3-N)	Drop-off #6	Pick-up DI>> (IL3-N) #2	Drop-off #7	Pick-up DI>> (IL3-N) #3

Assess	+	+	+	+	+	+	+	+
Tolerance	95,00 ms	40,00 ms	95,00 ms	40,00 ms	95,00 ms	40,00 ms	95,00 ms	40,00 ms
Trip (T1)	0	1	0	1	0	1	0	1
	Drop-off #8	Pick-up DI>> (IL3-N) #4	Drop-off #9	Pick-up DI>> (IL3-N) #5	Drop-off #10	Pick-up DI>> (IL2-IL3)	Drop-off #11	Pick-up DI>> (IL2-IL3) #2
Assess	+	+	+	+	+	+	+	+
Tolerance	95,00 ms	40,00 ms	95,00 ms	40,00 ms	95,00 ms	40,00 ms	95,00 ms	40,00 ms
Trip (T1)	0	1	0	1	0	1	0	1
	Drop-off #12	Pick-up DI>> (IL2-IL3) #3	Drop-off #13	Pick-up DI>> (IL2-IL3) #4	Drop-off #14	Pick-up DI>> (IL2-IL3) #5	Drop-off #15	Cold boot #1
Assess	+	+	+	+	+	+	+	+
Tolerance	95,00 ms	40,00 ms	95,00 ms	40,00 ms	95,00 ms	40,00 ms	95,00 ms	0,000 s
Trip (T1)	0	1	0	1	0	1	0	0
	No trip after boot (Grp1)							
Assess	+							
Tolerance	0,000 s							
Trip (T1)	0							

**Test State:**  
**Test passed**

## Test Settings



I3	700,0 mA 120,00 ° 50,000 Hz	700,0 mA 120,00 ° 50,000 Hz	700,0 mA 120,00 ° 50,000 Hz	700,0 mA 120,00 ° 50,000 Hz	700,0 mA 120,00 ° 50,000 Hz	700,0 mA 120,00 ° 50,000 Hz	700,0 mA 120,00 ° 50,000 Hz
I1'	962,0 mA 0,00 ° 50,000 Hz	962,0 mA 0,00 ° 50,000 Hz	962,0 mA 0,00 ° 50,000 Hz	962,0 mA 0,00 ° 50,000 Hz	962,0 mA 0,00 ° 50,000 Hz	962,0 mA 0,00 ° 50,000 Hz	962,0 mA 0,00 ° 50,000 Hz
I2'	962,0 mA -120,00 ° 50,000 Hz	0,000 A -120,00 ° 50,000 Hz	962,0 mA -120,00 ° 50,000 Hz	962,0 mA -120,00 ° 50,000 Hz	962,0 mA -120,00 ° 50,000 Hz	962,0 mA -120,00 ° 50,000 Hz	962,0 mA -120,00 ° 50,000 Hz
I3'	962,0 mA 120,00 ° 50,000 Hz	962,0 mA 120,00 ° 50,000 Hz	962,0 mA 120,00 ° 50,000 Hz	0,000 A 120,00 ° 50,000 Hz	962,0 mA 120,00 ° 50,000 Hz	962,0 mA 120,00 ° 50,000 Hz	962,0 mA 120,00 ° 50,000 Hz

## Test Module

Name:	OMICRON State Sequencer	Version:	3.00 SR 2
Test Start:	05-joulu-2014 17:32:45	Test End:	05-joulu-2014 17:32:46
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

## Test Results

### Time Assessment

Name	Ignore before	Start	Stop	Tnom	Tdev-	Tdev+	Tact	Tdev	Assess
Phase IL1 fault alarm	Phase IL1 CT fault	Phase IL1 CT fault	Power swing 0>1	60,00 ms	40,00 ms	0,000 s	55,70 ms	-4,300 ms	+
Phase IL2 fault alarm	Phase IL2 CT fault	Phase IL2 CT fault	Power swing 0>1	60,00 ms	40,00 ms	0,000 s	46,20 ms	-13,80 ms	+
Phase IL3 fault alarm	Phase IL3 CT fault	Phase IL3 CT fault	Power swing 0>1	60,00 ms	40,00 ms	0,000 s	56,00 ms	-4,000 ms	+
Phase IL'1 fault alarm	Phase IL'1 CT fault	Phase IL'1 CT fault	Power swing 0>1	60,00 ms	40,00 ms	0,000 s	56,10 ms	-3,900 ms	+
Phase IL'2 fault alarm	Phase IL'2 CT fault	Phase IL'2 CT fault	Power swing 0>1	60,00 ms	40,00 ms	0,000 s	45,90 ms	-14,10 ms	+
Phase IL'3 fault alarm	Phase IL'3 CT fault	Phase IL'3 CT fault	Power swing 0>1	60,00 ms	40,00 ms	0,000 s	56,00 ms	-4,000 ms	+
Phase IL1 CT fault trip	Phase IL1 CT fault	Phase IL1 CT fault	Trip (T1) 0>1	50,00 ms	50,00 ms	0,000 s	44,80 ms	-5,200 ms	+
Phase IL2 CT fault trip	Phase IL2 CT fault	Phase IL2 CT fault	Trip (T1) 0>1	50,00 ms	50,00 ms	0,000 s	34,70 ms	-15,30 ms	+
Phase IL3 CT fault trip	Phase IL3 CT fault	Phase IL3 CT fault	Trip (T1) 0>1	50,00 ms	50,00 ms	0,000 s	34,50 ms	-15,50 ms	+
Phase IL'1 CT fault trip	Phase IL'1 CT fault	Phase IL'1 CT fault	Trip (T1) 0>1	50,00 ms	50,00 ms	0,000 s	44,50 ms	-5,500 ms	+
Phase IL'2 CT fault trip	Phase IL'2 CT fault	Phase IL'2 CT fault	Trip (T1) 0>1	50,00 ms	50,00 ms	0,000 s	34,50 ms	-15,50 ms	+
Phase IL'3 CT fault trip	Phase IL'3 CT fault	Phase IL'3 CT fault	Trip (T1) 0>1	50,00 ms	50,00 ms	0,000 s	34,70 ms	-15,30 ms	+

Assess: + .. Passed x .. Failed o .. Not assessed

### State Assessment

	Normal situation	Phase IL1 CT fault	Normal situation 2	Phase IL2 CT fault	Normal situation 3	Phase IL3 CT fault	Normal situation 4	Phase IL'1 CT fault
Assess	+	+	+	+	+	+	+	+
Tolerance	0,000 s	50,00 ms	95,00 ms	50,00 ms	95,00 ms	50,00 ms	95,00 ms	50,00 ms



<b>I1'</b>	962,0 mA 0,00 ° 50,000 Hz	962,0 mA 0,00 ° 50,000 Hz	962,0 mA 0,00 ° 50,000 Hz	962,0 mA 0,00 ° 50,000 Hz	962,0 mA 0,00 ° 50,000 Hz	962,0 mA 0,00 ° 50,000 Hz	962,0 mA 0,00 ° 50,000 Hz
<b>I2'</b>	962,0 mA -120,00 ° 50,000 Hz	0,000 A -120,00 ° 50,000 Hz	962,0 mA -120,00 ° 50,000 Hz	962,0 mA -120,00 ° 50,000 Hz	962,0 mA -120,00 ° 50,000 Hz	962,0 mA -120,00 ° 50,000 Hz	962,0 mA -120,00 ° 50,000 Hz
<b>I3'</b>	962,0 mA 120,00 ° 50,000 Hz	962,0 mA 120,00 ° 50,000 Hz	962,0 mA 120,00 ° 50,000 Hz	0,000 A 120,00 ° 50,000 Hz	962,0 mA 120,00 ° 50,000 Hz	962,0 mA 120,00 ° 50,000 Hz	962,0 mA 120,00 ° 50,000 Hz

## Test Module

Name: OMICRON State Sequencer      Version: 3.00 SR 2  
 Test Start: 05-joulu-2014 17:36:18      Test End: 05-joulu-2014 17:36:20  
 User Name: Jesse Saastamoinen      Manager:  
 Company: Schneider Electric - Vamp

## Test Results

### Time Assessment

Name	Ignore before	Start	Stop	Tnom	Tdev-	Tdev+	Tact	Tdev	Assess
Phase IL1 fault alarm	Phase IL1 CT fault	Phase IL1 CT fault	Power swing 0>1	60,00 ms	40,00 ms	0,000 s	57,20 ms	-2,800 ms	+
Phase IL2 fault alarm	Phase IL2 CT fault	Phase IL2 CT fault	Power swing 0>1	60,00 ms	40,00 ms	0,000 s	47,60 ms	-12,40 ms	+
Phase IL3 fault alarm	Phase IL3 CT fault	Phase IL3 CT fault	Power swing 0>1	60,00 ms	40,00 ms	0,000 s	57,30 ms	-2,700 ms	+
Phase IL'1 fault alarm	Phase IL'1 CT fault	Phase IL'1 CT fault	Power swing 0>1	60,00 ms	40,00 ms	0,000 s	57,30 ms	-2,700 ms	+
Phase IL'2 fault alarm	Phase IL'2 CT fault	Phase IL'2 CT fault	Power swing 0>1	60,00 ms	40,00 ms	0,000 s	47,30 ms	-12,70 ms	+
Phase IL'3 fault alarm	Phase IL'3 CT fault	Phase IL'3 CT fault	Power swing 0>1	60,00 ms	40,00 ms	0,000 s	57,10 ms	-2,900 ms	+

Assess: + .. Passed x .. Failed o .. Not assessed

### State Assessment

	Normal situation	Phase IL1 CT fault	Normal situation 2	Phase IL2 CT fault	Normal situation 3	Phase IL3 CT fault	Normal situation 4	Phase IL'1 CT fault
<b>Assess</b>	+	+	+	+	+	+	+	+
<b>Tolerance</b>	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s
<b>Trip (T1)</b>	0	0	0	0	0	0	0	0
	Normal situation 5	Phase IL'2 CT fault	Normal situation 6	Phase IL'3 CT fault	Normal situation 7	Cold boot #1	No trip after boot (Grp1)	
<b>Assess</b>	+	+	+	+	+	+	+	
<b>Tolerance</b>	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s	
<b>Trip (T1)</b>	0	0	0	0	0	0	0	

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:

Test passed

Vampset: 87

Test State:

Command executed

Test passed

## Test Module

Name: OMICRON ExeCute  
Test Start: 05-joulu-2014 17:37:39  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
Test End: 05-joulu-2014 17:38:29  
Manager:

## Differential CTS Block test:

### Test Settings

State	Normal situation	Phase IL1 CT fault	Normal situation 2	Phase IL2 CT fault	Normal situation 3	Phase IL3 CT fault	Normal situation 4	Phase IL'1 CT fault
I 1	700,0 mA 0,00 ° 50,000 Hz	0,000 A 0,00 ° 50,000 Hz	700,0 mA 0,00 ° 50,000 Hz	700,0 mA 0,00 ° 50,000 Hz	700,0 mA 0,00 ° 50,000 Hz	700,0 mA 0,00 ° 50,000 Hz	700,0 mA 0,00 ° 50,000 Hz	700,0 mA 0,00 ° 50,000 Hz
I 2	700,0 mA -120,00 ° 50,000 Hz	700,0 mA -120,00 ° 50,000 Hz	700,0 mA -120,00 ° 50,000 Hz	0,000 A -120,00 ° 50,000 Hz	700,0 mA -120,00 ° 50,000 Hz	700,0 mA -120,00 ° 50,000 Hz	700,0 mA -120,00 ° 50,000 Hz	700,0 mA -120,00 ° 50,000 Hz
I 3	700,0 mA 120,00 ° 50,000 Hz	700,0 mA 120,00 ° 50,000 Hz	700,0 mA 120,00 ° 50,000 Hz	700,0 mA 120,00 ° 50,000 Hz	700,0 mA 120,00 ° 50,000 Hz	0,000 A 120,00 ° 50,000 Hz	700,0 mA 120,00 ° 50,000 Hz	700,0 mA 120,00 ° 50,000 Hz
I1'	962,0 mA 0,00 ° 50,000 Hz	962,0 mA 0,00 ° 50,000 Hz	962,0 mA 0,00 ° 50,000 Hz	962,0 mA 0,00 ° 50,000 Hz	962,0 mA 0,00 ° 50,000 Hz	962,0 mA 0,00 ° 50,000 Hz	962,0 mA 0,00 ° 50,000 Hz	0,000 A 0,00 ° 50,000 Hz
I2'	962,0 mA -120,00 ° 50,000 Hz	962,0 mA -120,00 ° 50,000 Hz	962,0 mA -120,00 ° 50,000 Hz	962,0 mA -120,00 ° 50,000 Hz	962,0 mA -120,00 ° 50,000 Hz	962,0 mA -120,00 ° 50,000 Hz	962,0 mA -120,00 ° 50,000 Hz	962,0 mA -120,00 ° 50,000 Hz
I3'	962,0 mA 120,00 ° 50,000 Hz	962,0 mA 120,00 ° 50,000 Hz	962,0 mA 120,00 ° 50,000 Hz	962,0 mA 120,00 ° 50,000 Hz	962,0 mA 120,00 ° 50,000 Hz	962,0 mA 120,00 ° 50,000 Hz	962,0 mA 120,00 ° 50,000 Hz	962,0 mA 120,00 ° 50,000 Hz
State	Normal situation 5	Phase IL'2 CT fault	Normal situation 6	Phase IL'3 CT fault	Normal situation 7	Cold boot #1	No trip after boot (Grp1)	
I 1	700,0 mA 0,00 ° 50,000 Hz	700,0 mA 0,00 ° 50,000 Hz	700,0 mA 0,00 ° 50,000 Hz	700,0 mA 0,00 ° 50,000 Hz	700,0 mA 0,00 ° 50,000 Hz	700,0 mA 0,00 ° 50,000 Hz	700,0 mA 0,00 ° 50,000 Hz	
I 2	700,0 mA -120,00 ° 50,000 Hz	700,0 mA -120,00 ° 50,000 Hz	700,0 mA -120,00 ° 50,000 Hz	700,0 mA -120,00 ° 50,000 Hz	700,0 mA -120,00 ° 50,000 Hz	700,0 mA -120,00 ° 50,000 Hz	700,0 mA -120,00 ° 50,000 Hz	
I 3	700,0 mA 120,00 ° 50,000 Hz	700,0 mA 120,00 ° 50,000 Hz	700,0 mA 120,00 ° 50,000 Hz	700,0 mA 120,00 ° 50,000 Hz	700,0 mA 120,00 ° 50,000 Hz	700,0 mA 120,00 ° 50,000 Hz	700,0 mA 120,00 ° 50,000 Hz	
I1'	962,0 mA 0,00 ° 50,000 Hz	962,0 mA 0,00 ° 50,000 Hz	962,0 mA 0,00 ° 50,000 Hz	962,0 mA 0,00 ° 50,000 Hz	962,0 mA 0,00 ° 50,000 Hz	962,0 mA 0,00 ° 50,000 Hz	962,0 mA 0,00 ° 50,000 Hz	
I2'	962,0 mA -120,00 ° 50,000 Hz	0,000 A -120,00 ° 50,000 Hz	962,0 mA -120,00 ° 50,000 Hz	962,0 mA -120,00 ° 50,000 Hz	962,0 mA -120,00 ° 50,000 Hz	962,0 mA -120,00 ° 50,000 Hz	962,0 mA -120,00 ° 50,000 Hz	
I3'	962,0 mA 120,00 ° 50,000 Hz	962,0 mA 120,00 ° 50,000 Hz	962,0 mA 120,00 ° 50,000 Hz	0,000 A 120,00 ° 50,000 Hz	962,0 mA 120,00 ° 50,000 Hz	962,0 mA 120,00 ° 50,000 Hz	962,0 mA 120,00 ° 50,000 Hz	

## Test Module

Name: OMICRON State Sequencer  
Test Start: 05-joulu-2014 17:39:51  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
Test End: 05-joulu-2014 17:39:53  
Manager:

## Test Results

## Time Assessment

Name	Ignore before	Start	Stop	Tnom	Tdev-	Tdev+	Tact	Tdev	Assess
Phase IL1 fault alarm	Phase IL1 CT fault	Phase IL1 CT fault	Power swing 0>1	60,00 ms	40,00 ms	0,000 s	51,50 ms	-8,500 ms	+
Phase IL2 fault alarm	Phase IL2 CT fault	Phase IL2 CT fault	Power swing 0>1	60,00 ms	40,00 ms	0,000 s	51,30 ms	-8,700 ms	+
Phase IL3 fault alarm	Phase IL3 CT fault	Phase IL3 CT fault	Power swing 0>1	60,00 ms	40,00 ms	0,000 s	51,50 ms	-8,500 ms	+
Phase IL'1 fault alarm	Phase IL'1 CT fault	Phase IL'1 CT fault	Power swing 0>1	60,00 ms	40,00 ms	0,000 s	51,40 ms	-8,600 ms	+
Phase IL'2 fault alarm	Phase IL'2 CT fault	Phase IL'2 CT fault	Power swing 0>1	60,00 ms	40,00 ms	0,000 s	51,20 ms	-8,800 ms	+
Phase IL'3 fault alarm	Phase IL'3 CT fault	Phase IL'3 CT fault	Power swing 0>1	60,00 ms	40,00 ms	0,000 s	51,40 ms	-8,600 ms	+

Assess: + .. Passed x .. Failed o .. Not assessed

## State Assessment

	Normal situation	Phase IL1 CT fault	Normal situation 2	Phase IL2 CT fault	Normal situation 3	Phase IL3 CT fault	Normal situation 4	Phase IL'1 CT fault
Assess	+	+	+	+	+	+	+	+
Tolerance	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s
Trip (T1)	0	0	0	0	0	0	0	0
	Normal situation 5	Phase IL'2 CT fault	Normal situation 6	Phase IL'3 CT fault	Normal situation 7	Cold boot #1	No trip after boot (Grp1)	
Assess	+	+	+	+	+	+	+	
Tolerance	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s	
Trip (T1)	0	0	0	0	0	0	0	

Assess: + .. Passed x .. Failed o .. Not assessed

### Test State:

Test passed

## Vampset: Disable stages

### Test State:

Command executed

Test passed

## Test Module

Name: OMICRON ExeCute  
 Test Start: 05-joulu-2014 17:41:13  
 User Name: Jesse Saastamoinen  
 Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
 Test End: 05-joulu-2014 17:41:33  
 Manager:

## Vampset: 87

### Test State:

Command executed

Test passed

## Test Module

Name: OMICRON ExeCute  
 Test Start: 05-joulu-2014 17:42:53  
 User Name: Jesse Saastamoinen

Version: 3.00 SR 2  
 Test End: 05-joulu-2014 17:43:38  
 Manager:

**Operation time DI> (1.2xIset) harm. enabled:**

[illegible]

I2'	0,000 A -120,00 ° 50,000 Hz	0,000 A -120,00 ° 50,000 Hz	0,000 A -120,00 ° 50,000 Hz	0,000 A -120,00 ° 50,000 Hz	0,000 A -120,00 ° 50,000 Hz	2,117 A 0,00 ° 50,000 Hz	0,000 A -120,00 ° 50,000 Hz	2,117 A 0,00 ° 50,000 Hz
I3'	0,000 A 120,00 ° 50,000 Hz	2,117 A 120,00 ° 50,000 Hz	0,000 A 120,00 ° 50,000 Hz	2,117 A 120,00 ° 50,000 Hz	0,000 A 120,00 ° 50,000 Hz	2,117 A 180,00 ° 50,000 Hz	0,000 A 120,00 ° 50,000 Hz	2,117 A 180,00 ° 50,000 Hz
State	Drop-off #12	Pick-up DI> (IL2-IL3) #3	Drop-off #13	Pick-up DI> (IL2-IL3) #4	Drop-off #14	Pick-up DI> (IL2-IL3) #5	Drop-off #15	Cold boot #1
I 1	0,000 A 0,00 ° 50,000 Hz	0,000 A 0,00 ° 50,000 Hz	0,000 A 0,00 ° 50,000 Hz	0,000 A 0,00 ° 50,000 Hz	0,000 A 0,00 ° 50,000 Hz	0,000 A 0,00 ° 50,000 Hz	0,000 A 0,00 ° 50,000 Hz	700,0 mA 0,00 ° 50,000 Hz
I 2	0,000 A -120,00 ° 50,000 Hz	2,379 A 0,00 ° 50,000 Hz	0,000 A -120,00 ° 50,000 Hz	2,379 A 0,00 ° 50,000 Hz	0,000 A -120,00 ° 50,000 Hz	2,379 A 0,00 ° 50,000 Hz	0,000 A -120,00 ° 50,000 Hz	700,0 mA -120,00 ° 50,000 Hz
I 3	0,000 A 120,00 ° 50,000 Hz	2,379 A 180,00 ° 50,000 Hz	0,000 A 120,00 ° 50,000 Hz	2,379 A 180,00 ° 50,000 Hz	0,000 A 120,00 ° 50,000 Hz	2,379 A 180,00 ° 50,000 Hz	0,000 A 120,00 ° 50,000 Hz	700,0 mA 120,00 ° 50,000 Hz
I1'	0,000 A 0,00 ° 50,000 Hz	0,000 A 0,00 ° 50,000 Hz	0,000 A 0,00 ° 50,000 Hz	0,000 A 0,00 ° 50,000 Hz	0,000 A 0,00 ° 50,000 Hz	0,000 A 0,00 ° 50,000 Hz	0,000 A 0,00 ° 50,000 Hz	962,0 mA 0,00 ° 50,000 Hz
I2'	0,000 A -120,00 ° 50,000 Hz	2,117 A 0,00 ° 50,000 Hz	0,000 A -120,00 ° 50,000 Hz	2,117 A 0,00 ° 50,000 Hz	0,000 A -120,00 ° 50,000 Hz	2,117 A 0,00 ° 50,000 Hz	0,000 A -120,00 ° 50,000 Hz	962,0 mA -120,00 ° 50,000 Hz
I3'	0,000 A 120,00 ° 50,000 Hz	2,117 A 180,00 ° 50,000 Hz	0,000 A 120,00 ° 50,000 Hz	2,117 A 180,00 ° 50,000 Hz	0,000 A 120,00 ° 50,000 Hz	2,117 A 180,00 ° 50,000 Hz	0,000 A 120,00 ° 50,000 Hz	962,0 mA 120,00 ° 50,000 Hz
State	No trip after boot (Grp1)							
I 1	700,0 mA 0,00 ° 50,000 Hz							
I 2	700,0 mA -120,00 ° 50,000 Hz							
I 3	700,0 mA 120,00 ° 50,000 Hz							
I1'	962,0 mA 0,00 ° 50,000 Hz							
I2'	962,0 mA -120,00 ° 50,000 Hz							
I3'	962,0 mA 120,00 ° 50,000 Hz							

## Test Module

Name: OMICRON State Sequencer  
Test Start: 05-joulu-2014 17:45:02  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - Vamp

Version:  
Test End:  
Manager:

3.00 SR 2  
05-joulu-2014 17:45:03

## Test Results

## Time Assessment

Name	Ignore before	Start	Stop	Tnom	Tdev-	Tdev+	Tact	Tdev	Assess
DI> trip (IL1-IL2-IL3) #1	Pick-up DI> (IL1-IL2-IL3)	Pick-up DI> (IL1-IL2-IL3)	Trip (T1) 0>1	60,00 ms	60,00 ms	0,000 s	38,20 ms	-21,80 ms	+
DI> trip (IL1-IL2-IL3) #2	Pick-up DI> (IL1-IL2-IL3) #2	Pick-up DI> (IL1-IL2-IL3) #2	Trip (T1) 0>1	60,00 ms	60,00 ms	0,000 s	40,00 ms	-20,00 ms	+
DI> trip (IL1-IL2-IL3) #3	Pick-up DI> (IL1-IL2-IL3) #3	Pick-up DI> (IL1-IL2-IL3) #3	Trip (T1) 0>1	60,00 ms	60,00 ms	0,000 s	40,00 ms	-20,00 ms	+
DI> trip (IL1-IL2-IL3) #4	Pick-up DI> (IL1-IL2-IL3) #4	Pick-up DI> (IL1-IL2-IL3) #4	Trip (T1) 0>1	60,00 ms	60,00 ms	0,000 s	40,20 ms	-19,80 ms	+
DI> trip (IL1-IL2-IL3) #5	Pick-up DI> (IL1-IL2-IL3) #5	Pick-up DI> (IL1-IL2-IL3) #5	Trip (T1) 0>1	60,00 ms	60,00 ms	0,000 s	39,90 ms	-20,10 ms	+
DI> trip (IL3-N) #1	Pick-up DI> (IL3-N)	Pick-up DI> (IL3-N)	Trip (T1) 0>1	60,00 ms	60,00 ms	0,000 s	40,10 ms	-19,90 ms	+
DI> trip (IL3-N) #2	Pick-up DI> (IL3-N) #2	Pick-up DI> (IL3-N) #2	Trip (T1) 0>1	60,00 ms	60,00 ms	0,000 s	40,00 ms	-20,00 ms	+
DI> trip (IL3-N) #3	Pick-up DI> (IL3-N) #3	Pick-up DI> (IL3-N) #3	Trip (T1) 0>1	60,00 ms	60,00 ms	0,000 s	39,90 ms	-20,10 ms	+
DI> trip (IL3-N) #4	Pick-up DI> (IL3-N) #4	Pick-up DI> (IL3-N) #4	Trip (T1) 0>1	60,00 ms	60,00 ms	0,000 s	40,00 ms	-20,00 ms	+
DI> trip (IL3-N) #5	Pick-up DI> (IL3-N) #5	Pick-up DI> (IL3-N) #5	Trip (T1) 0>1	60,00 ms	60,00 ms	0,000 s	40,00 ms	-20,00 ms	+
DI> trip (IL2-IL3) #1	Pick-up DI> (IL2-IL3)	Pick-up DI> (IL2-IL3)	Trip (T1) 0>1	60,00 ms	60,00 ms	0,000 s	40,10 ms	-19,90 ms	+
DI> trip (IL2-IL3) #2	Pick-up DI> (IL2-IL3) #2	Pick-up DI> (IL2-IL3) #2	Trip (T1) 0>1	60,00 ms	60,00 ms	0,000 s	40,10 ms	-19,90 ms	+
DI> trip (IL2-IL3) #3	Pick-up DI> (IL2-IL3) #3	Pick-up DI> (IL2-IL3) #3	Trip (T1) 0>1	60,00 ms	60,00 ms	0,000 s	40,00 ms	-20,00 ms	+
DI> trip (IL2-IL3) #4	Pick-up DI> (IL2-IL3) #4	Pick-up DI> (IL2-IL3) #4	Trip (T1) 0>1	60,00 ms	60,00 ms	0,000 s	40,00 ms	-20,00 ms	+
DI> trip (IL2-IL3) #5	Pick-up DI> (IL2-IL3) #5	Pick-up DI> (IL2-IL3) #5	Trip (T1) 0>1	60,00 ms	60,00 ms	0,000 s	40,00 ms	-20,00 ms	+

Assess: + .. Passed x .. Failed o .. Not assessed

## State Assessment

	Normal situation	Pick-up DI> (IL1-IL2-IL3)	Drop-off	Pick-up DI> (IL1-IL2-IL3) #2	Drop-off #2	Pick-up DI> (IL1-IL2-IL3) #3	Drop-off #3	Pick-up DI> (IL1-IL2-IL3) #4
<b>Assess</b>	+	+	+	+	+	+	+	+
<b>Tolerance</b>	0,000 s	60,00 ms	95,00 ms	60,00 ms	95,00 ms	60,00 ms	95,00 ms	60,00 ms
<b>Trip (T1)</b>	0	1	0	1	0	1	0	1
	Drop-off #4	Pick-up DI> (IL1-IL2-IL3) #5	Drop-off #5	Pick-up DI> (IL3-N)	Drop-off #6	Pick-up DI> (IL3-N) #2	Drop-off #7	Pick-up DI> (IL3-N) #3



<b>Assess</b>	+	+	+	+	+	+	+	+
<b>Tolerance</b>	95,00 ms	60,00 ms	95,00 ms	60,00 ms	95,00 ms	60,00 ms	95,00 ms	60,00 ms
<b>Trip (T1)</b>	0	1	0	1	0	1	0	1
	<b>Drop-off #8</b>	<b>Pick-up DI&gt; (IL3-N) #4</b>	<b>Drop-off #9</b>	<b>Pick-up DI&gt; (IL3-N) #5</b>	<b>Drop-off #10</b>	<b>Pick-up DI&gt; (IL2-IL3)</b>	<b>Drop-off #11</b>	<b>Pick-up DI&gt; (IL2-IL3) #2</b>
<b>Assess</b>	+	+	+	+	+	+	+	+
<b>Tolerance</b>	95,00 ms	60,00 ms	95,00 ms	60,00 ms	95,00 ms	60,00 ms	95,00 ms	60,00 ms
<b>Trip (T1)</b>	0	1	0	1	0	1	0	1
	<b>Drop-off #12</b>	<b>Pick-up DI&gt; (IL2-IL3) #3</b>	<b>Drop-off #13</b>	<b>Pick-up DI&gt; (IL2-IL3) #4</b>	<b>Drop-off #14</b>	<b>Pick-up DI&gt; (IL2-IL3) #5</b>	<b>Drop-off #15</b>	<b>Cold boot #1</b>
<b>Assess</b>	+	+	+	+	+	+	+	+
<b>Tolerance</b>	95,00 ms	60,00 ms	95,00 ms	60,00 ms	95,00 ms	60,00 ms	95,00 ms	0,000 s
<b>Trip (T1)</b>	0	1	0	1	0	1	0	0
	<b>No trip after boot (Grp1)</b>							
<b>Assess</b>	+							
<b>Tolerance</b>	0,000 s							
<b>Trip (T1)</b>	0							

**Test State:**  
**Test passed**

## Test Settings

[illegible]

I3'	0,000 A 120,00 ° 50,000 Hz	1,009 A 180,00 ° 50,000 Hz	0,000 A 120,00 ° 50,000 Hz	1,009 A 180,00 ° 50,000 Hz	0,000 A 120,00 ° 50,000 Hz	1,009 A 180,00 ° 50,000 Hz	0,000 A 120,00 ° 50,000 Hz	962,0 mA 120,00 ° 50,000 Hz
State	No trip after boot (Grp1)							
I 1	700,0 mA 0,00 ° 50,000 Hz							
I 2	700,0 mA -120,00 ° 50,000 Hz							
I 3	700,0 mA 120,00 ° 50,000 Hz							
I1'	962,0 mA 0,00 ° 50,000 Hz							
I2'	962,0 mA -120,00 ° 50,000 Hz							
I3'	962,0 mA 120,00 ° 50,000 Hz							

## Test Module

Name: OMICRON State Sequencer  
 Test Start: 05-joulu-2014 17:46:27  
 User Name: Jesse Saastamoinen  
 Company: Schneider Electric - Vamp

Version:  
 Test End:  
 Manager:

3.00 SR 2  
 05-joulu-2014 17:46:28

## Test Results

## Time Assessment

Name	Ignore before	Start	Stop	Tnom	Tdev-	Tdev+	Tact	Tdev	Assess
DI> trip (IL1-IL2-IL3) #1	Pick-up DI> (IL1-IL2-IL3)	Pick-up DI> (IL1-IL2-IL3)	Trip (T1) 0>1	50,00 ms	50,00 ms	0,000 s	39,50 ms	-10,50 ms	+
DI> trip (IL1-IL2-IL3) #2	Pick-up DI> (IL1-IL2-IL3) #2	Pick-up DI> (IL1-IL2-IL3) #2	Trip (T1) 0>1	50,00 ms	50,00 ms	0,000 s	40,00 ms	-10,00 ms	+
DI> trip (IL1-IL2-IL3) #3	Pick-up DI> (IL1-IL2-IL3) #3	Pick-up DI> (IL1-IL2-IL3) #3	Trip (T1) 0>1	50,00 ms	50,00 ms	0,000 s	40,10 ms	-9,900 ms	+
DI> trip (IL1-IL2-IL3) #4	Pick-up DI> (IL1-IL2-IL3) #4	Pick-up DI> (IL1-IL2-IL3) #4	Trip (T1) 0>1	50,00 ms	50,00 ms	0,000 s	40,10 ms	-9,900 ms	+
DI> trip (IL1-IL2-IL3) #5	Pick-up DI> (IL1-IL2-IL3) #5	Pick-up DI> (IL1-IL2-IL3) #5	Trip (T1) 0>1	50,00 ms	50,00 ms	0,000 s	40,10 ms	-9,900 ms	+
DI> trip (IL3-N) #1	Pick-up DI> (IL3-N)	Pick-up DI> (IL3-N)	Trip (T1) 0>1	50,00 ms	50,00 ms	0,000 s	39,90 ms	-10,10 ms	+
DI> trip (IL3-N) #2	Pick-up DI> (IL3-N) #2	Pick-up DI> (IL3-N) #2	Trip (T1) 0>1	50,00 ms	50,00 ms	0,000 s	40,10 ms	-9,900 ms	+
DI> trip (IL3-N) #3	Pick-up DI> (IL3-N) #3	Pick-up DI> (IL3-N) #3	Trip (T1) 0>1	50,00 ms	50,00 ms	0,000 s	39,90 ms	-10,10 ms	+
DI> trip (IL3-N) #4	Pick-up DI> (IL3-N) #4	Pick-up DI> (IL3-N) #4	Trip (T1) 0>1	50,00 ms	50,00 ms	0,000 s	40,00 ms	-10,00 ms	+
DI> trip (IL3-N) #5	Pick-up DI> (IL3-N) #5	Pick-up DI> (IL3-N) #5	Trip (T1) 0>1	50,00 ms	50,00 ms	0,000 s	39,90 ms	-10,10 ms	+
DI> trip (IL2-IL3) #1	Pick-up DI> (IL2-IL3)	Pick-up DI> (IL2-IL3)	Trip (T1) 0>1	50,00 ms	50,00 ms	0,000 s	40,30 ms	-9,700 ms	+
DI> trip (IL2-IL3) #2	Pick-up DI> (IL2-IL3) #2	Pick-up DI> (IL2-IL3) #2	Trip (T1) 0>1	50,00 ms	50,00 ms	0,000 s	39,90 ms	-10,10 ms	+
DI> trip (IL2-IL3) #3	Pick-up DI> (IL2-IL3) #3	Pick-up DI> (IL2-IL3) #3	Trip (T1) 0>1	50,00 ms	50,00 ms	0,000 s	40,10 ms	-9,900 ms	+
DI> trip (IL2-IL3) #4	Pick-up DI> (IL2-IL3) #4	Pick-up DI> (IL2-IL3) #4	Trip (T1) 0>1	50,00 ms	50,00 ms	0,000 s	40,10 ms	-9,900 ms	+
DI> trip (IL2-IL3) #5	Pick-up DI> (IL2-IL3) #5	Pick-up DI> (IL2-IL3) #5	Trip (T1) 0>1	50,00 ms	50,00 ms	0,000 s	39,90 ms	-10,10 ms	+

Assess: + .. Passed x .. Failed o .. Not assessed

## State Assessment

	Normal situation	Pick-up DI> (IL1-IL2-IL3)	Drop-off	Pick-up DI> (IL1-IL2-IL3) #2	Drop-off #2	Pick-up DI> (IL1-IL2-IL3) #3	Drop-off #3	Pick-up DI> (IL1-IL2-IL3) #4
Assess	+	+	+	+	+	+	+	+
Tolerance	0,000 s	50,00 ms	95,00 ms	50,00 ms	95,00 ms	50,00 ms	95,00 ms	50,00 ms
Trip (T1)	0	1	0	1	0	1	0	1
	Drop-off #4	Pick-up DI> (IL1-IL2-IL3) #5	Drop-off #5	Pick-up DI> (IL3-N)	Drop-off #6	Pick-up DI> (IL3-N) #2	Drop-off #7	Pick-up DI> (IL3-N) #3

<b>Assess</b>	+	+	+	+	+	+	+	+
<b>Tolerance</b>	95,00 ms	50,00 ms	95,00 ms	50,00 ms	95,00 ms	50,00 ms	95,00 ms	50,00 ms
<b>Trip (T1)</b>	0	1	0	1	0	1	0	1
	<b>Drop-off #8</b>	<b>Pick-up DI&gt; (IL3-N) #4</b>	<b>Drop-off #9</b>	<b>Pick-up DI&gt; (IL3-N) #5</b>	<b>Drop-off #10</b>	<b>Pick-up DI&gt; (IL2-IL3)</b>	<b>Drop-off #11</b>	<b>Pick-up DI&gt; (IL2-IL3) #2</b>
<b>Assess</b>	+	+	+	+	+	+	+	+
<b>Tolerance</b>	95,00 ms	50,00 ms	95,00 ms	50,00 ms	95,00 ms	50,00 ms	95,00 ms	50,00 ms
<b>Trip (T1)</b>	0	1	0	1	0	1	0	1
	<b>Drop-off #12</b>	<b>Pick-up DI&gt; (IL2-IL3) #3</b>	<b>Drop-off #13</b>	<b>Pick-up DI&gt; (IL2-IL3) #4</b>	<b>Drop-off #14</b>	<b>Pick-up DI&gt; (IL2-IL3) #5</b>	<b>Drop-off #15</b>	<b>Cold boot #1</b>
<b>Assess</b>	+	+	+	+	+	+	+	+
<b>Tolerance</b>	95,00 ms	50,00 ms	95,00 ms	50,00 ms	95,00 ms	50,00 ms	95,00 ms	0,000 s
<b>Trip (T1)</b>	0	1	0	1	0	1	0	0
	<b>No trip after boot (Grp1)</b>							
<b>Assess</b>	+							
<b>Tolerance</b>	0,000 s							
<b>Trip (T1)</b>	0							

**Test State:**  
**Test passed**

## Test Settings

[illegible]

I3'	0,000 A 120,00 ° 50,000 Hz	241,0 mA 180,00 ° 50,000 Hz	0,000 A 120,00 ° 50,000 Hz	241,0 mA 180,00 ° 50,000 Hz	0,000 A 120,00 ° 50,000 Hz	241,0 mA 180,00 ° 50,000 Hz	0,000 A 120,00 ° 50,000 Hz	962,0 mA 120,00 ° 50,000 Hz
State	No trip after boot (Grp1)							
I 1	700,0 mA 0,00 ° 50,000 Hz							
I 2	700,0 mA -120,00 ° 50,000 Hz							
I 3	700,0 mA 120,00 ° 50,000 Hz							
I1'	962,0 mA 0,00 ° 50,000 Hz							
I2'	962,0 mA -120,00 ° 50,000 Hz							
I3'	962,0 mA 120,00 ° 50,000 Hz							

## Test Module

Name: OMICRON State Sequencer  
 Test Start: 05-joulu-2014 17:47:53  
 User Name: Jesse Saastamoinen  
 Company: Schneider Electric - Vamp

Version:  
 Test End:  
 Manager:

3.00 SR 2  
 05-joulu-2014 17:47:54

## Test Results

## Time Assessment

Name	Ignore before	Start	Stop	Tnom	Tdev-	Tdev+	Tact	Tdev	Assess
DI>> trip (IL1-IL2-IL3) #1	Pick-up DI>> (IL1-IL2-IL3)	Pick-up DI>> (IL1-IL2-IL3)	Trip (T1) 0>1	40,00 ms	40,00 ms	0,000 s	34,60 ms	-5,400 ms	+
DI>> trip (IL1-IL2-IL3) #2	Pick-up DI>> (IL1-IL2-IL3) #2	Pick-up DI>> (IL1-IL2-IL3) #2	Trip (T1) 0>1	40,00 ms	40,00 ms	0,000 s	30,20 ms	-9,800 ms	+
DI>> trip (IL1-IL2-IL3) #3	Pick-up DI>> (IL1-IL2-IL3) #3	Pick-up DI>> (IL1-IL2-IL3) #3	Trip (T1) 0>1	40,00 ms	40,00 ms	0,000 s	30,00 ms	-10,00 ms	+
DI>> trip (IL1-IL2-IL3) #4	Pick-up DI>> (IL1-IL2-IL3) #4	Pick-up DI>> (IL1-IL2-IL3) #4	Trip (T1) 0>1	40,00 ms	40,00 ms	0,000 s	30,00 ms	-10,00 ms	+
DI>> trip (IL1-IL2-IL3) #5	Pick-up DI>> (IL1-IL2-IL3) #5	Pick-up DI>> (IL1-IL2-IL3) #5	Trip (T1) 0>1	40,00 ms	40,00 ms	0,000 s	30,00 ms	-10,00 ms	+
DI>> trip (IL3-N) #1	Pick-up DI>> (IL3-N)	Pick-up DI>> (IL3-N)	Trip (T1) 0>1	40,00 ms	40,00 ms	0,000 s	30,00 ms	-10,00 ms	+
DI>> trip (IL3-N) #2	Pick-up DI>> (IL3-N) #2	Pick-up DI>> (IL3-N) #2	Trip (T1) 0>1	40,00 ms	40,00 ms	0,000 s	29,90 ms	-10,10 ms	+
DI>> trip (IL3-N) #3	Pick-up DI>> (IL3-N) #3	Pick-up DI>> (IL3-N) #3	Trip (T1) 0>1	40,00 ms	40,00 ms	0,000 s	30,10 ms	-9,900 ms	+
DI>> trip (IL3-N) #4	Pick-up DI>> (IL3-N) #4	Pick-up DI>> (IL3-N) #4	Trip (T1) 0>1	40,00 ms	40,00 ms	0,000 s	30,10 ms	-9,900 ms	+
DI>> trip (IL3-N) #5	Pick-up DI>> (IL3-N) #5	Pick-up DI>> (IL3-N) #5	Trip (T1) 0>1	40,00 ms	40,00 ms	0,000 s	30,00 ms	-10,00 ms	+
DI>> trip (IL2-IL3) #1	Pick-up DI>> (IL2-IL3)	Pick-up DI>> (IL2-IL3)	Trip (T1) 0>1	40,00 ms	40,00 ms	0,000 s	30,00 ms	-10,00 ms	+
DI>> trip (IL2-IL3) #2	Pick-up DI>> (IL2-IL3) #2	Pick-up DI>> (IL2-IL3) #2	Trip (T1) 0>1	40,00 ms	40,00 ms	0,000 s	30,00 ms	-10,00 ms	+
DI>> trip (IL2-IL3) #3	Pick-up DI>> (IL2-IL3) #3	Pick-up DI>> (IL2-IL3) #3	Trip (T1) 0>1	40,00 ms	40,00 ms	0,000 s	30,10 ms	-9,900 ms	+
DI>> trip (IL2-IL3) #4	Pick-up DI>> (IL2-IL3) #4	Pick-up DI>> (IL2-IL3) #4	Trip (T1) 0>1	40,00 ms	40,00 ms	0,000 s	30,20 ms	-9,800 ms	+
DI>> trip (IL2-IL3) #5	Pick-up DI>> (IL2-IL3) #5	Pick-up DI>> (IL2-IL3) #5	Trip (T1) 0>1	40,00 ms	40,00 ms	0,000 s	29,90 ms	-10,10 ms	+

Assess: + .. Passed x .. Failed o .. Not assessed

## State Assessment

	Normal situation	Pick-up DI>> (IL1-IL2-IL3)	Drop-off	Pick-up DI>> (IL1-IL2-IL3) #2	Drop-off #2	Pick-up DI>> (IL1-IL2-IL3) #3	Drop-off #3	Pick-up DI>> (IL1-IL2-IL3) #4
Assess	+	+	+	+	+	+	+	+
Tolerance	0,000 s	40,00 ms	95,00 ms	40,00 ms	95,00 ms	40,00 ms	95,00 ms	40,00 ms
Trip (T1)	0	1	0	1	0	1	0	1
	Drop-off #4	Pick-up DI>> (IL1-IL2-IL3) #5	Drop-off #5	Pick-up DI>> (IL3-N)	Drop-off #6	Pick-up DI>> (IL3-N) #2	Drop-off #7	Pick-up DI>> (IL3-N) #3



Assess	+	+	+	+	+	+	+	+
Tolerance	95,00 ms	40,00 ms	95,00 ms	40,00 ms	95,00 ms	40,00 ms	95,00 ms	40,00 ms
Trip (T1)	0	1	0	1	0	1	0	1
	Drop-off #8	Pick-up DI>> (IL3-N) #4	Drop-off #9	Pick-up DI>> (IL3-N) #5	Drop-off #10	Pick-up DI>> (IL2-IL3) #11	Drop-off #11	Pick-up DI>> (IL2-IL3) #2
Assess	+	+	+	+	+	+	+	+
Tolerance	95,00 ms	40,00 ms	95,00 ms	40,00 ms	95,00 ms	40,00 ms	95,00 ms	40,00 ms
Trip (T1)	0	1	0	1	0	1	0	1
	Drop-off #12	Pick-up DI>> (IL2-IL3) #3	Drop-off #13	Pick-up DI>> (IL2-IL3) #4	Drop-off #14	Pick-up DI>> (IL2-IL3) #5	Drop-off #15	Cold boot #1
Assess	+	+	+	+	+	+	+	+
Tolerance	95,00 ms	40,00 ms	95,00 ms	40,00 ms	95,00 ms	40,00 ms	95,00 ms	0,000 s
Trip (T1)	0	1	0	1	0	1	0	0
	No trip after boot (Grp1)							
Assess	+							
Tolerance	0,000 s							
Trip (T1)	0							

Assess: + .. Passed x .. Failed o .. Not assessed

**Test State:**  
Test passed

## Test Object - Device Settings

### Substation/Bay:

Substation:  
Bay:

Substation address:  
Bay address:

### Device:

Name/description: CT="1A", CT'="1A"  
Device type:  
Serial/model number:  
Additional info 1:  
Additional info 2:

Manufacturer:  
Device address:

## Vampset: Disable stages

**Test State:**  
Command executed  
Test passed

### Test Module

Name: OMICRON ExeCute  
Test Start: 05-joulu-2014 17:49:13  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
Test End: 05-joulu-2014 17:49:34  
Manager:

## Vampset: 87

**Test State:**  
Command executed  
Test passed

### Test Module

Name: OMICRON ExeCute Version: 3.00 SR 2

Test Start: 05-joulu-2014 17:50:53  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - Vamp

Test End: 05-joulu-2014 17:51:38  
Manager:

## Curve check $DI \geq \max$ , Slope1= $\max$ , Bias= $\max$ , Slope2= $\max$ , $DI > \max$

### Test Module

Name: OMICRON Diff Operating  
Characteristic  
Test Start: 05-joulu-2014 17:53:00  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
Test End: 05-joulu-2014 17:53:00  
Manager:

### Test Results for Fault Type L3-L1 at Reference Side Primary

Idiff	Ibias	Nominal Trip Time	Actual Trip Time	State	Result
0,49 In	0,30 In	N/T	N/T	Tested	Passed
1,95 In	2,00 In	N/T	N/T	Tested	Passed
5,85 In	4,50 In	N/T	N/T	Tested	Passed
9,75 In	6,50 In	N/T	N/T	Tested	Passed
10,25 In	7,15 In	0,0200 s	0,0467 s	Tested	Passed
6,15 In	4,50 In	0,0400 s	0,0433 s	Tested	Passed
2,05 In	2,00 In	0,0400 s	0,0540 s	Tested	Passed
0,51 In	0,30 In	0,0400 s	0,0546 s	Tested	Passed

#### Test State:

Test passed

8 out of 8 points tested.

8 points passed.

0 points failed.

### Harmonic check (2nd) limit= $\min$

### Test Module

Name: OMICRON Diff Harmonic  
Restraint  
Test Start: 05-joulu-2014 17:54:22  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
Test End: 05-joulu-2014 17:54:33  
Manager:

### Test Results for Testphase L1-L2-L3 at Reference Side Primary for 2. Harmonic

Idiff	Ixf/Idiff	Angle (Ixf,Idiff)	Trip	State	Result
3,50 I/In	4,00 %	0,0 °	Yes	Tested	Passed
3,50 I/In	4,00 %	-120,0 °	Yes	Tested	Passed
3,50 I/In	4,00 %	120,0 °	Yes	Tested	Passed
3,50 I/In	6,00 %	0,0 °	No	Tested	Passed
3,50 I/In	6,00 %	-120,0 °	No	Tested	Passed
3,50 I/In	6,00 %	120,0 °	No	Tested	Passed
8,00 I/In	4,00 %	0,0 °	Yes	Tested	Passed
8,00 I/In	4,00 %	-120,0 °	Yes	Tested	Passed
8,00 I/In	4,00 %	120,0 °	Yes	Tested	Passed
8,00 I/In	6,00 %	0,0 °	No	Tested	Passed
8,00 I/In	6,00 %	-120,0 °	No	Tested	Passed
8,00 I/In	6,00 %	120,0 °	No	Tested	Passed
10,30 I/In	6,00 %	0,0 °	Yes	Tested	Passed
10,30 I/In	6,00 %	-120,0 °	Yes	Tested	Passed
10,30 I/In	6,00 %	120,0 °	Yes	Tested	Passed

**State:**

15 out of 15 points tested.  
15 points passed.  
0 points failed.

**General Assessment: Test passed**

**Harmonic check (5nd) limit=min****Test Module**

Name:	OMICRON Diff Harmonic Restraint	Version:	3.00 SR 2
Test Start:	05-joulu-2014 17:55:55	Test End:	05-joulu-2014 17:56:07
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

**Test Results for Testphase L1-L2-L3 at Reference Side Primary for 5. Harmonic**

Idiff	Ixf/Idiff	Angle (Ixf,Idiff)	Trip	State	Result
3,50 I/In	19,00 %	0,0 °	Yes	Tested	Passed
3,50 I/In	19,00 %	-120,0 °	Yes	Tested	Passed
3,50 I/In	19,00 %	120,0 °	Yes	Tested	Passed
3,50 I/In	21,00 %	0,0 °	No	Tested	Passed
3,50 I/In	21,00 %	-120,0 °	No	Tested	Passed
3,50 I/In	21,00 %	120,0 °	No	Tested	Passed
8,00 I/In	19,00 %	0,0 °	Yes	Tested	Passed
8,00 I/In	19,00 %	-120,0 °	Yes	Tested	Passed
8,00 I/In	19,00 %	120,0 °	Yes	Tested	Passed
8,00 I/In	21,00 %	0,0 °	No	Tested	Passed
8,00 I/In	21,00 %	-120,0 °	No	Tested	Passed
8,00 I/In	21,00 %	120,0 °	No	Tested	Passed
10,30 I/In	21,00 %	0,0 °	Yes	Tested	Passed
10,30 I/In	21,00 %	-120,0 °	Yes	Tested	Passed
10,30 I/In	21,00 %	120,0 °	Yes	Tested	Passed

**State:**

15 out of 15 points tested.  
15 points passed.  
0 points failed.

**General Assessment: Test passed**

**Test Object - Device Settings****Substation/Bay:**

Substation:	Substation address:
Bay:	Bay address:

**Device:**

Name/description:	CT="1A", CT'="1A"	Manufacturer:
Device type:		Device address:
Serial/model number:		
Additional info 1:		
Additional info 2:		

**Vampset: Disable stages****Test State:**

**Command executed**  
**Test passed**

## Test Module

Name:	OMICRON ExeCute	Version:	3.00 SR 2
Test Start:	05-joulu-2014 22:40:24	Test End:	05-joulu-2014 22:40:41
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

## Vampset: 87

### Test State:

Command executed

Test passed

## Test Module

Name:	OMICRON ExeCute	Version:	3.00 SR 2
Test Start:	05-joulu-2014 22:42:28	Test End:	05-joulu-2014 22:43:13
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

## Harmonic check (2nd) limit=max

## Test Module

Name:	OMICRON Diff Harmonic Restraint	Version:	3.00 SR 2
Test Start:	05-joulu-2014 18:01:11	Test End:	05-joulu-2014 18:01:41
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

## Test Results for Testphase L1-L2-L3 at Reference Side Primary for 2. Harmonic

Idiff	Ixf/Idiff	Angle (Ixf,Idiff)	Trip	State	Result
0,50 I/In	29,00 %	0,0 °	Yes	Tested	Passed
0,50 I/In	29,00 %	-120,0 °	Yes	Tested	Passed
0,50 I/In	29,00 %	120,0 °	Yes	Tested	Passed
0,50 I/In	31,00 %	0,0 °	No	Tested	Passed
0,50 I/In	31,00 %	-120,0 °	No	Tested	Passed
0,50 I/In	31,00 %	120,0 °	No	Tested	Passed
3,50 I/In	29,00 %	0,0 °	Yes	Tested	Passed
3,50 I/In	29,00 %	-120,0 °	Yes	Tested	Passed
3,50 I/In	29,00 %	120,0 °	Yes	Tested	Passed
3,50 I/In	31,00 %	0,0 °	No	Tested	Passed
3,50 I/In	31,00 %	-120,0 °	No	Tested	Passed
3,50 I/In	31,00 %	120,0 °	No	Tested	Passed
6,50 I/In	29,00 %	0,0 °	Yes	Tested	Passed
6,50 I/In	29,00 %	-120,0 °	Yes	Tested	Passed
6,50 I/In	29,00 %	120,0 °	Yes	Tested	Passed
6,50 I/In	31,00 %	0,0 °	No	Tested	Passed
6,50 I/In	31,00 %	-120,0 °	No	Tested	Passed
6,50 I/In	31,00 %	120,0 °	No	Tested	Passed
9,90 I/In	29,00 %	0,0 °	Yes	Tested	Passed
9,90 I/In	29,00 %	-120,0 °	Yes	Tested	Passed
9,90 I/In	29,00 %	120,0 °	Yes	Tested	Passed
9,70 I/In	31,00 %	0,0 °	No	Tested	Passed
9,70 I/In	31,00 %	-120,0 °	No	Tested	Passed
9,70 I/In	31,00 %	120,0 °	No	Tested	Passed

### State:

24 out of 24 points tested.

24 points passed.

0 points failed.

**General Assessment: Test passed**

## Test Object - Device Settings

**Substation/Bay:**

Substation:  
Bay:

Substation address:  
Bay address:

**Device:**

Name/description: CT="1A", CT'="1A"  
Device type:  
Serial/model number:  
Additional info 1:  
Additional info 2:

Manufacturer:  
Device address:

**Harmonic check (5nd) limit=max****Test Module**

Name: OMICRON Diff Harmonic  
Restraint  
Test Start: 05-joulu-2014 22:49:53  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
Test End: 05-joulu-2014 22:50:41  
Manager:

**Test Results for Testphase L1-L2-L3 at Reference Side Primary for 5. Harmonic**

Idiff	Ixf/Idiff	Angle (Ixf,Idiff)	Trip	State	Result
0,50 I/In	47,50 %	0,0 °	No	Tested	Failed
0,50 I/In	47,50 %	-120,0 °	Yes	Tested	Passed
0,50 I/In	47,50 %	120,0 °	No	Tested	Failed
0,50 I/In	52,50 %	0,0 °	No	Tested	Passed
0,50 I/In	52,50 %	-120,0 °	No	Tested	Passed
0,50 I/In	52,50 %	120,0 °	No	Tested	Passed
3,50 I/In	52,50 %	0,0 °	No	Tested	Passed
3,50 I/In	52,50 %	-120,0 °	No	Tested	Passed
3,50 I/In	52,50 %	120,0 °	No	Tested	Passed
3,50 I/In	47,50 %	0,0 °	Yes	Tested	Passed
3,50 I/In	47,50 %	-120,0 °	Yes	Tested	Passed
3,50 I/In	47,50 %	120,0 °	Yes	Tested	Passed
6,50 I/In	47,50 %	0,0 °	Yes	Tested	Passed
6,50 I/In	47,50 %	-120,0 °	Yes	Tested	Passed
6,50 I/In	47,50 %	120,0 °	Yes	Tested	Passed
6,50 I/In	52,50 %	0,0 °	No	Tested	Passed
6,50 I/In	52,50 %	-120,0 °	No	Tested	Passed
6,50 I/In	52,50 %	120,0 °	No	Tested	Passed
9,70 I/In	52,50 %	0,0 °	No	Tested	Passed
9,70 I/In	52,50 %	-120,0 °	No	Tested	Passed
9,70 I/In	52,50 %	120,0 °	No	Tested	Passed
9,90 I/In	47,50 %	0,0 °	Yes	Tested	Passed
9,90 I/In	47,50 %	-120,0 °	Yes	Tested	Passed
9,90 I/In	47,50 %	120,0 °	Yes	Tested	Passed

**State:**

24 out of 24 points tested.

22 points passed.

2 points failed.

**General Assessment: Test failed**

**Test Object - Device Settings****Substation/Bay:**

Substation:  
Bay:

Substation address:  
Bay address:

**Device:**

Name/description: CT="1A", CT'="1A"  
Device type:  
Serial/model number:  
Additional info 1:  
Additional info 2:

Manufacturer:  
Device address:

**Vampset: Disable stages****Test State:**

Command executed

Test passed

**Test Module**

Name: OMICRON ExeCute  
Test Start: 05-joulu-2014 18:05:10  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
Test End: 05-joulu-2014 18:05:26  
Manager:

**Vampset: 87****Test State:**

Command executed

Test passed

**Test Module**

Name: OMICRON ExeCute  
Test Start: 05-joulu-2014 18:06:46  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
Test End: 05-joulu-2014 18:08:01  
Manager:

**Curve check  $DI \geq 20\%$ , Slope1=50%, Bias=2, Slope2=100%, YnYn6****Test Module**

Name: OMICRON Diff Operating Characteristic  
Test Start: 05-joulu-2014 18:09:23  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
Test End: 05-joulu-2014 18:09:23  
Manager:

**Test Results for Fault Type L1-L2-L3 at Reference Side Primary**

Idiff	Ibias	Nominal Trip Time	Actual Trip Time	State	Result
0,19 In	0,33 In	N/T	N/T	Tested	Passed
0,39 In	0,90 In	N/T	N/T	Tested	Passed
0,97 In	2,05 In	N/T	N/T	Tested	Passed
3,90 In	5,05 In	N/T	N/T	Tested	Passed
4,10 In	5,05 In	0,0400 s	0,0443 s	Tested	Passed
1,03 In	2,05 In	0,0400 s	0,0517 s	Tested	Passed
0,41 In	0,90 In	0,0400 s	0,0591 s	Tested	Passed
0,21 In	0,33 In	0,0400 s	0,0528 s	Tested	Passed

**Test State:**

Test passed

8 out of 8 points tested.

8 points passed.

0 points failed.

**Curve check (compensation) YnYn6****Test Module**

Name:	OMICRON Diff Operating Characteristic	Version:	3.00 SR 2
Test Start:	05-joulu-2014 18:10:45	Test End:	05-joulu-2014 18:10:49
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

## Test Results for Fault Type L1-E at Reference Side Primary

Idiff	Ibias	Nominal Trip Time	Actual Trip Time	State	Result
0,24 In	0,60 In	N/T	N/T	Tested	Passed
0,39 In	1,00 In	N/T	N/T	Tested	Passed
0,97 In	2,20 In	N/T	N/T	Tested	Passed
1,95 In	4,10 In	N/T	N/T	Tested	Passed
3,90 In	6,10 In	N/T	N/T	Tested	Passed
4,10 In	6,10 In	0,0400 s	0,0408 s	Tested	Passed
2,05 In	4,10 In	0,0400 s	0,0564 s	Tested	Passed
1,03 In	2,20 In	0,0400 s	0,0563 s	Tested	Passed
0,41 In	1,00 In	0,0400 s	0,0535 s	Tested	Passed
0,26 In	0,60 In	0,0400 s	0,0571 s	Tested	Passed

### Test State:

Test passed

10 out of 10 points tested.

10 points passed.

0 points failed.

## Test Object - Device Settings

### Substation/Bay:

Substation:  
Bay:

Substation address:  
Bay address:

### Device:

Name/description: CT="1A", CT'="1A"  
Device type:  
Serial/model number:  
Additional info 1:  
Additional info 2:

Manufacturer:  
Device address:

## Vampset: Disable stages

### Test State:

Command executed

Test passed

### Test Module

Name: OMICRON ExeCute  
Test Start: 05-joulu-2014 18:12:08  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
Test End: 05-joulu-2014 18:12:25  
Manager:

## Vampset: 87

### Test State:

Command executed

Test passed

### Test Module

Name: OMICRON ExeCute  
Version: 3.00 SR 2

Test Start: 05-joulu-2014 18:13:44  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - Vamp

Test End:  
Manager:

05-joulu-2014 18:14:59

## Curve check $DI \geq 20\%$ , Slope1=50%, Bias=2, Slope2=100%, YnD1

### Test Module

Name: OMICRON Diff Operating  
Characteristic  
Test Start: 05-joulu-2014 18:16:21  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
Test End: 05-joulu-2014 18:16:21  
Manager:

### Test Results for Fault Type L1-L2-L3 at Reference Side Primary

Idiff	Ibias	Nominal Trip Time	Actual Trip Time	State	Result
0,19 In	0,33 In	N/T	N/T	Tested	Passed
0,39 In	0,90 In	N/T	N/T	Tested	Passed
0,97 In	2,05 In	N/T	N/T	Tested	Passed
3,90 In	5,05 In	N/T	N/T	Tested	Passed
4,10 In	5,05 In	0,0400 s	0,0358 s	Tested	Passed
1,03 In	2,05 In	0,0400 s	0,0560 s	Tested	Passed
0,41 In	0,90 In	0,0400 s	0,0513 s	Tested	Passed
0,21 In	0,33 In	0,0400 s	0,0558 s	Tested	Passed

#### Test State:

Test passed

8 out of 8 points tested.

8 points passed.

0 points failed.

## Curve check (compensation) YnD1

### Test Module

Name: OMICRON Diff Operating  
Characteristic  
Test Start: 05-joulu-2014 18:17:43  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
Test End: 05-joulu-2014 18:17:47  
Manager:

### Test Results for Fault Type L1-E at Reference Side Primary

Idiff	Ibias	Nominal Trip Time	Actual Trip Time	State	Result
0,24 In	0,60 In	N/T	N/T	Tested	Passed
0,39 In	1,00 In	N/T	N/T	Tested	Passed
0,97 In	2,20 In	N/T	N/T	Tested	Passed
1,95 In	4,10 In	N/T	N/T	Tested	Passed
3,90 In	6,10 In	N/T	N/T	Tested	Passed
4,10 In	6,10 In	0,0400 s	0,0421 s	Tested	Passed
2,05 In	4,10 In	0,0400 s	0,0575 s	Tested	Passed
1,03 In	2,20 In	0,0400 s	0,0559 s	Tested	Passed
0,41 In	1,00 In	0,0400 s	0,0526 s	Tested	Passed
0,26 In	0,60 In	0,0400 s	0,0524 s	Tested	Passed

#### Test State:

Test passed

10 out of 10 points tested.

10 points passed.

0 points failed.



## Test Object - Device Settings

### Substation/Bay:

Substation:  
Bay:

Substation address:  
Bay address:

### Device:

Name/description: CT="1A", CT'="1A"  
Device type:  
Serial/model number:  
Additional info 1:  
Additional info 2:

Manufacturer:  
Device address:

## Vampset: Disable stages

### Test State:

Command executed  
Test passed

### Test Module

Name: OMICRON ExeCute  
Test Start: 05-joulu-2014 18:19:07  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
Test End: 05-joulu-2014 18:19:23  
Manager:

## Vampset: 87

### Test State:

Command executed  
Test passed

### Test Module

Name: OMICRON ExeCute  
Test Start: 05-joulu-2014 18:20:43  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
Test End: 05-joulu-2014 18:21:57  
Manager:

## Curve check $DI \geq 20\%$ , Slope1=50%, Bias=2, Slope2=100%, YnD5

### Test Module

Name: OMICRON Diff Operating Characteristic  
Test Start: 05-joulu-2014 18:23:19  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
Test End: 05-joulu-2014 18:23:19  
Manager:

## Test Results for Fault Type L1-L2-L3 at Reference Side Primary

Idiff	Ibias	Nominal Trip Time	Actual Trip Time	State	Result
0,19 In	0,33 In	N/T	N/T	Tested	Passed
0,39 In	0,90 In	N/T	N/T	Tested	Passed
0,97 In	2,05 In	N/T	N/T	Tested	Passed
3,90 In	5,05 In	N/T	N/T	Tested	Passed
4,10 In	5,05 In	0,0400 s	0,0425 s	Tested	Passed
1,03 In	2,05 In	0,0400 s	0,0479 s	Tested	Passed
0,41 In	0,90 In	0,0400 s	0,0570 s	Tested	Passed
0,21 In	0,33 In	0,0400 s	0,0523 s	Tested	Passed

**Test State:****Test passed**

8 out of 8 points tested.

8 points passed.

0 points failed.

**Curve check (compensation) YnD5****Test Module**

Name:	OMICRON Diff Operating Characteristic	Version:	3.00 SR 2
Test Start:	05-joulu-2014 18:24:41	Test End:	05-joulu-2014 18:24:45
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

**Test Results for Fault Type L1-E at Reference Side Primary**

Idiff	Ibias	Nominal Trip Time	Actual Trip Time	State	Result
0,24 In	0,60 In	N/T	N/T	Tested	Passed
0,39 In	1,00 In	N/T	N/T	Tested	Passed
0,97 In	2,20 In	N/T	N/T	Tested	Passed
1,95 In	4,10 In	N/T	N/T	Tested	Passed
3,90 In	6,10 In	N/T	N/T	Tested	Passed
4,10 In	6,10 In	0,0400 s	0,0453 s	Tested	Passed
2,05 In	4,10 In	0,0400 s	0,0477 s	Tested	Passed
1,03 In	2,20 In	0,0400 s	0,0508 s	Tested	Passed
0,41 In	1,00 In	0,0400 s	0,0557 s	Tested	Passed
0,26 In	0,60 In	0,0400 s	0,0538 s	Tested	Passed

**Test State:****Test passed**

10 out of 10 points tested.

10 points passed.

0 points failed.

**Test Object - Device Settings****Substation/Bay:**

Substation:	Substation address:
Bay:	Bay address:

**Device:**

Name/description:	CT="1A", CT'="1A"	Manufacturer:
Device type:		Device address:
Serial/model number:		
Additional info 1:		
Additional info 2:		

**Vampset: Disable stages****Test State:****Command executed****Test passed****Test Module**

Name:	OMICRON ExeCute	Version:	3.00 SR 2
Test Start:	05-joulu-2014 18:26:05	Test End:	05-joulu-2014 18:26:21
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

**Vampset: 87**

**Test State:**  
**Command executed**  
**Test passed**

## Test Module

Name:	OMICRON ExeCute	Version:	3.00 SR 2
Test Start:	05-joulu-2014 18:27:41	Test End:	05-joulu-2014 18:28:56
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

## Curve check $DI \geq 20\%$ , Slope1=50%, Bias=2, Slope2=100%, YnD7

## Test Module

Name:	OMICRON Diff Operating Characteristic	Version:	3.00 SR 2
Test Start:	05-joulu-2014 18:30:17	Test End:	05-joulu-2014 18:30:18
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

## Test Results for Fault Type L1-L2-L3 at Reference Side Primary

Idiff	Ibias	Nominal Trip Time	Actual Trip Time	State	Result
0,19 In	0,33 In	N/T	N/T	Tested	Passed
0,39 In	0,90 In	N/T	N/T	Tested	Passed
0,97 In	2,05 In	N/T	N/T	Tested	Passed
3,90 In	5,05 In	N/T	N/T	Tested	Passed
4,10 In	5,05 In	0,0400 s	0,0429 s	Tested	Passed
1,03 In	2,05 In	0,0400 s	0,0472 s	Tested	Passed
0,41 In	0,90 In	0,0400 s	0,0574 s	Tested	Passed
0,21 In	0,33 In	0,0400 s	0,0508 s	Tested	Passed

**Test State:**  
**Test passed**  
8 out of 8 points tested.  
8 points passed.  
0 points failed.

## Curve check (compensation) YnD7

## Test Module

Name:	OMICRON Diff Operating Characteristic	Version:	3.00 SR 2
Test Start:	05-joulu-2014 18:31:39	Test End:	05-joulu-2014 18:31:43
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

## Test Results for Fault Type L1-E at Reference Side Primary

Idiff	Ibias	Nominal Trip Time	Actual Trip Time	State	Result
0,24 In	0,60 In	N/T	N/T	Tested	Passed
0,39 In	1,00 In	N/T	N/T	Tested	Passed
0,97 In	2,20 In	N/T	N/T	Tested	Passed
1,95 In	4,10 In	N/T	N/T	Tested	Passed
3,90 In	6,10 In	N/T	N/T	Tested	Passed
4,10 In	6,10 In	0,0400 s	0,0375 s	Tested	Passed
2,05 In	4,10 In	0,0400 s	0,0539 s	Tested	Passed
1,03 In	2,20 In	0,0400 s	0,0522 s	Tested	Passed
0,41 In	1,00 In	0,0400 s	0,0505 s	Tested	Passed
0,26 In	0,60 In	0,0400 s	0,0535 s	Tested	Passed

**Test State:****Test passed**

10 out of 10 points tested.

10 points passed.

0 points failed.

**Test Object - Device Settings****Substation/Bay:**Substation:  
Bay:Substation address:  
Bay address:**Device:**Name/description: CT="1A", CT'="1A"  
Device type:  
Serial/model number:  
Additional info 1:  
Additional info 2:Manufacturer:  
Device address:**Vampset: Disable stages****Test State:****Command executed****Test passed****Test Module**Name: OMICRON ExeCute  
Test Start: 05-joulu-2014 18:33:02  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - VampVersion: 3.00 SR 2  
Test End: 05-joulu-2014 18:33:19  
Manager:**Vampset: 87****Test State:****Command executed****Test passed****Test Module**Name: OMICRON ExeCute  
Test Start: 05-joulu-2014 18:34:38  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - VampVersion: 3.00 SR 2  
Test End: 05-joulu-2014 18:35:53  
Manager:**Curve check  $DI \geq 20\%$ , Slope1=50%, Bias=2, Slope2=100%, YnD11****Test Module**Name: OMICRON Diff Operating  
Characteristic  
Test Start: 05-joulu-2014 18:37:14  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - VampVersion: 3.00 SR 2  
Test End: 05-joulu-2014 18:37:14  
Manager:**Test Results for Fault Type L1-L2-L3 at Reference Side Primary**

Idiff	Ibias	Nominal Trip Time	Actual Trip Time	State	Result
0,19 In	0,33 In	N/T	N/T	Tested	Passed
0,39 In	0,90 In	N/T	N/T	Tested	Passed
0,97 In	2,05 In	N/T	N/T	Tested	Passed
3,90 In	5,05 In	N/T	N/T	Tested	Passed
4,10 In	5,05 In	0,0400 s	0,0369 s	Tested	Passed
1,03 In	2,05 In	0,0400 s	0,0545 s	Tested	Passed
0,41 In	0,90 In	0,0400 s	0,0524 s	Tested	Passed
0,21 In	0,33 In	0,0400 s	0,0584 s	Tested	Passed

#### Test State:

Test passed

8 out of 8 points tested.

8 points passed.

0 points failed.

## Curve check (compensation) YnD11

### Test Module

Name:	OMICRON Diff Operating Characteristic	Version:	3.00 SR 2
Test Start:	05-joulu-2014 18:38:36	Test End:	05-joulu-2014 18:38:40
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

### Test Results for Fault Type L1-E at Reference Side Primary

Idiff	Ibias	Nominal Trip Time	Actual Trip Time	State	Result
0,24 In	0,60 In	N/T	N/T	Tested	Passed
0,39 In	1,00 In	N/T	N/T	Tested	Passed
0,97 In	2,20 In	N/T	N/T	Tested	Passed
1,95 In	4,10 In	N/T	N/T	Tested	Passed
3,90 In	6,10 In	N/T	N/T	Tested	Passed
4,10 In	6,10 In	0,0400 s	0,0450 s	Tested	Passed
2,05 In	4,10 In	0,0400 s	0,0526 s	Tested	Passed
1,03 In	2,20 In	0,0400 s	0,0564 s	Tested	Passed
0,41 In	1,00 In	0,0400 s	0,0574 s	Tested	Passed
0,26 In	0,60 In	0,0400 s	0,0560 s	Tested	Passed

#### Test State:

Test passed

10 out of 10 points tested.

10 points passed.

0 points failed.

## Test Object - Device Settings

### Substation/Bay:

Substation:	Substation address:
Bay:	Bay address:

### Device:

Name/description:	CT="1A", CT'="1A"	Manufacturer:	
Device type:		Device address:	
Serial/model number:			
Additional info 1:			
Additional info 2:			

## Vampset: Disable stages

**Test State:**  
**Command executed**  
**Test passed**

### Test Module

Name:	OMICRON ExeCute	Version:	3.00 SR 2
Test Start:	05-joulu-2014 18:39:59	Test End:	05-joulu-2014 18:40:15
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

**Vampset: 87**

**Test State:**  
**Command executed**  
**Test passed**

### Test Module

Name:	OMICRON ExeCute	Version:	3.00 SR 2
Test Start:	05-joulu-2014 18:41:34	Test End:	05-joulu-2014 18:42:49
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

**Curve check  $DI \geq 20\%$ , Slope1=50%, Bias=2, Slope2=100%, Dyn1**

### Test Module

Name:	OMICRON Diff Operating Characteristic	Version:	3.00 SR 2
Test Start:	05-joulu-2014 18:44:10	Test End:	05-joulu-2014 18:44:11
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

### Test Results for Fault Type L1-L2-L3 at Reference Side Primary

Idiff	Ibias	Nominal Trip Time	Actual Trip Time	State	Result
0,19 In	0,33 In	N/T	N/T	Tested	Passed
0,39 In	0,90 In	N/T	N/T	Tested	Passed
0,97 In	2,05 In	N/T	N/T	Tested	Passed
3,90 In	5,05 In	N/T	N/T	Tested	Passed
4,10 In	5,05 In	0,0400 s	0,0398 s	Tested	Passed
1,03 In	2,05 In	0,0400 s	0,0534 s	Tested	Passed
0,41 In	0,90 In	0,0400 s	0,0501 s	Tested	Passed
0,21 In	0,33 In	0,0400 s	0,0546 s	Tested	Passed

**Test State:**  
**Test passed**  
8 out of 8 points tested.  
8 points passed.  
0 points failed.

**Curve check (compensation) Dyn1**

### Test Module

Name:	OMICRON Diff Operating Characteristic	Version:	3.00 SR 2
Test Start:	05-joulu-2014 18:45:32	Test End:	05-joulu-2014 18:45:43
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

### Test Results for Fault Type L1-E at Reference Side Primary

Idiff	Ibias	Nominal Trip Time	Actual Trip Time	State	Result
0,24 In	0,60 In	N/T	N/T	Tested	Passed
0,39 In	1,00 In	N/T	N/T	Tested	Passed
0,97 In	2,20 In	N/T	N/T	Tested	Passed
1,95 In	4,10 In	N/T	N/T	Tested	Passed
3,90 In	6,10 In	N/T	N/T	Tested	Passed
4,10 In	6,10 In	0,0400 s	N/T	Tested	Failed
2,05 In	4,10 In	0,0400 s	N/T	Tested	Failed
1,03 In	2,20 In	0,0400 s	N/T	Tested	Failed
0,41 In	1,00 In	0,0400 s	N/T	Tested	Failed
0,26 In	0,60 In	0,0400 s	0,0499 s	Tested	Passed

#### Test State:

Test failed

10 out of 10 points tested.

6 points passed.

4 points failed.

## Test Object - Device Settings

#### Substation/Bay:

Substation:

Bay:

Substation address:

Bay address:

#### Device:

Name/description: CT="1A", CT'="1A"

Device type:

Serial/model number:

Additional info 1:

Additional info 2:

Manufacturer:

Device address:

## Vampset: Disable stages

#### Test State:

Command executed

Test passed

#### Test Module

Name: OMICRON ExeCute  
Test Start: 05-joulu-2014 18:47:02  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
Test End: 05-joulu-2014 18:47:18  
Manager:

## Vampset: 87

#### Test State:

Command executed

Test passed

#### Test Module

Name: OMICRON ExeCute  
Test Start: 05-joulu-2014 18:48:37  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
Test End: 05-joulu-2014 18:49:52  
Manager:

## Curve check DI>=20%,Slope1=50%,Bias=2,Slope2=100%,Dyn5

#### Test Module

Name: OMICRON Diff Operating Characteristic  
Test Start: 05-joulu-2014 18:51:14

Version: 3.00 SR 2  
Test End: 05-joulu-2014 18:51:14

User Name: Jesse Saastamoinen  
Company: Schneider Electric - Vamp

Manager:

## Test Results for Fault Type L1-L2-L3 at Reference Side Primary

Idiff	Ibias	Nominal Trip Time	Actual Trip Time	State	Result
0,19 In	0,33 In	N/T	N/T	Tested	Passed
0,39 In	0,90 In	N/T	N/T	Tested	Passed
0,97 In	2,05 In	N/T	N/T	Tested	Passed
3,90 In	5,05 In	N/T	N/T	Tested	Passed
4,10 In	5,05 In	0,0400 s	0,0348 s	Tested	Passed
1,03 In	2,05 In	0,0400 s	0,0554 s	Tested	Passed
0,41 In	0,90 In	0,0400 s	0,0516 s	Tested	Passed
0,21 In	0,33 In	0,0400 s	0,0568 s	Tested	Passed

### Test State:

Test passed

8 out of 8 points tested.

8 points passed.

0 points failed.

## Curve check (compensation) Dyn5

### Test Module

Name: OMICRON Diff Operating  
Characteristic  
Test Start: 05-joulu-2014 18:52:35  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
Test End: 05-joulu-2014 18:52:46  
Manager:

## Test Results for Fault Type L1-E at Reference Side Primary

Idiff	Ibias	Nominal Trip Time	Actual Trip Time	State	Result
0,24 In	0,60 In	N/T	N/T	Tested	Passed
0,39 In	1,00 In	N/T	N/T	Tested	Passed
0,97 In	2,20 In	N/T	N/T	Tested	Passed
1,95 In	4,10 In	N/T	N/T	Tested	Passed
3,90 In	6,10 In	N/T	N/T	Tested	Passed
4,10 In	6,10 In	0,0400 s	N/T	Tested	Failed
2,05 In	4,10 In	0,0400 s	N/T	Tested	Failed
1,03 In	2,20 In	0,0400 s	N/T	Tested	Failed
0,41 In	1,00 In	0,0400 s	N/T	Tested	Failed
0,26 In	0,60 In	0,0400 s	0,0503 s	Tested	Passed

### Test State:

Test failed

10 out of 10 points tested.

6 points passed.

4 points failed.

## Test Object - Device Settings

### Substation/Bay:

Substation:  
Bay:

Substation address:  
Bay address:



**Device:**

Name/description: CT="1A", CT'="1A"  
Device type:  
Serial/model number:  
Additional info 1:  
Additional info 2:

Manufacturer:  
Device address:

**Vampset: Disable stages****Test State:**

Command executed

Test passed

**Test Module**

Name: OMICRON ExeCute  
Test Start: 05-joulu-2014 18:54:05  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
Test End: 05-joulu-2014 18:54:22  
Manager:

**Vampset: 87****Test State:**

Command executed

Test passed

**Test Module**

Name: OMICRON ExeCute  
Test Start: 05-joulu-2014 18:55:40  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
Test End: 05-joulu-2014 18:56:55  
Manager:

**Curve check  $DI \geq 20\%$ , Slope1=50%, Bias=2, Slope2=100%, Dyn7****Test Module**

Name: OMICRON Diff Operating Characteristic  
Test Start: 05-joulu-2014 18:58:16  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
Test End: 05-joulu-2014 18:58:17  
Manager:

**Test Results for Fault Type L1-L2-L3 at Reference Side Primary**

Idiff	Ibias	Nominal Trip Time	Actual Trip Time	State	Result
0,19 In	0,33 In	N/T	N/T	Tested	Passed
0,39 In	0,90 In	N/T	N/T	Tested	Passed
0,97 In	2,05 In	N/T	N/T	Tested	Passed
3,90 In	5,05 In	N/T	N/T	Tested	Passed
4,10 In	5,05 In	0,0400 s	0,0429 s	Tested	Passed
1,03 In	2,05 In	0,0400 s	0,0487 s	Tested	Passed
0,41 In	0,90 In	0,0400 s	0,0554 s	Tested	Passed
0,21 In	0,33 In	0,0400 s	0,0494 s	Tested	Passed

**Test State:**

Test passed

8 out of 8 points tested.

8 points passed.

0 points failed.

**Curve check (compensation) Dyn7****Test Module**

Name:	OMICRON Diff Operating Characteristic	Version:	3.00 SR 2
Test Start:	05-joulu-2014 18:59:38	Test End:	05-joulu-2014 19:00:01
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

## Test Results for Fault Type L1-E at Reference Side Primary

Idiff	Ibias	Nominal Trip Time	Actual Trip Time	State	Result
0,24 In	0,60 In	N/T	0,0772 s	Tested	Failed
0,39 In	1,00 In	N/T	N/T	Tested	Passed
0,97 In	2,20 In	N/T	N/T	Tested	Passed
1,95 In	4,10 In	N/T	N/T	Tested	Passed
3,90 In	6,10 In	N/T	N/T	Tested	Passed
4,10 In	6,10 In	0,0400 s	N/T	Tested	Failed
2,05 In	4,10 In	0,0400 s	N/T	Tested	Failed
1,03 In	2,20 In	0,0400 s	N/T	Tested	Failed
0,41 In	1,00 In	0,0400 s	N/T	Tested	Failed
0,26 In	0,60 In	0,0400 s	0,0593 s	Tested	Passed

### Test State:

Test failed

10 out of 10 points tested.

5 points passed.

5 points failed.

## Test Object - Device Settings

### Substation/Bay:

Substation:

Bay:

Substation address:

Bay address:

### Device:

Name/description: CT="1A", CT'="1A"

Device type:

Serial/model number:

Additional info 1:

Additional info 2:

Manufacturer:

Device address:

## Vampset: Disable stages

### Test State:

Command executed

Test passed

## Test Module

Name:	OMICRON ExeCute
Test Start:	05-joulu-2014 19:01:21
User Name:	Jesse Saastamoinen
Company:	Schneider Electric - Vamp

Version:	3.00 SR 2
Test End:	05-joulu-2014 19:01:37
Manager:	

## Vampset: 87

### Test State:

Command executed

Test passed

## Test Module

Name:	OMICRON ExeCute
Test Start:	05-joulu-2014 19:02:56
User Name:	Jesse Saastamoinen
Company:	Schneider Electric - Vamp

Version:	3.00 SR 2
Test End:	05-joulu-2014 19:04:11
Manager:	

## Test Module

Name: OMICRON Diff Operating Characteristic Version: 3.00 SR 2  
Test Start: 05-joulu-2014 19:05:33 Test End: 05-joulu-2014 19:05:33  
User Name: Jesse Saastamoinen Manager:  
Company: Schneider Electric - Vamp

## Test Results for Fault Type L1-L2-L3 at Reference Side Primary

Idiff	Ibias	Nominal Trip Time	Actual Trip Time	State	Result
0,19 In	0,33 In	N/T	N/T	Tested	Passed
0,39 In	0,90 In	N/T	N/T	Tested	Passed
0,97 In	2,05 In	N/T	N/T	Tested	Passed
3,90 In	5,05 In	N/T	N/T	Tested	Passed
4,10 In	5,05 In	0,0400 s	0,0362 s	Tested	Passed
1,03 In	2,05 In	0,0400 s	0,0471 s	Tested	Passed
0,41 In	0,90 In	0,0400 s	0,0531 s	Tested	Passed
0,21 In	0,33 In	0,0400 s	0,0540 s	Tested	Passed

### Test State:

Test passed

8 out of 8 points tested.

8 points passed.

0 points failed.

## Curve check (compensation) Dyn11

## Test Module

Name: OMICRON Diff Operating Characteristic Version: 3.00 SR 2  
Test Start: 05-joulu-2014 19:06:55 Test End: 05-joulu-2014 19:07:18  
User Name: Jesse Saastamoinen Manager:  
Company: Schneider Electric - Vamp

## Test Results for Fault Type L1-E at Reference Side Primary

Idiff	Ibias	Nominal Trip Time	Actual Trip Time	State	Result
0,24 In	0,60 In	N/T	0,1779 s	Tested	Failed
0,39 In	1,00 In	N/T	N/T	Tested	Passed
0,97 In	2,20 In	N/T	N/T	Tested	Passed
1,95 In	4,10 In	N/T	N/T	Tested	Passed
3,90 In	6,10 In	N/T	N/T	Tested	Passed
4,10 In	6,10 In	0,0400 s	N/T	Tested	Failed
2,05 In	4,10 In	0,0400 s	N/T	Tested	Failed
1,03 In	2,20 In	0,0400 s	N/T	Tested	Failed
0,41 In	1,00 In	0,0400 s	N/T	Tested	Failed
0,26 In	0,60 In	0,0400 s	0,0514 s	Tested	Passed

### Test State:

Test failed

10 out of 10 points tested.

5 points passed.

5 points failed.

## Test Object - Device Settings

### Substation/Bay:

Substation:  
Bay:

Substation address:  
Bay address:

**Device:**

Name/description: CT="1A", CT'="1A"  
 Device type:  
 Serial/model number:  
 Additional info 1:  
 Additional info 2:

Manufacturer:  
 Device address:

**Vampset: Disable stages****Test State:****Command executed****Test passed****Test Module**

Name: OMICRON ExeCute  
 Test Start: 05-joulu-2014 19:08:37  
 User Name: Jesse Saastamoinen  
 Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
 Test End: 05-joulu-2014 19:08:54  
 Manager:

**Vampset: 87****Test State:****Command executed****Test passed****Test Module**

Name: OMICRON ExeCute  
 Test Start: 05-joulu-2014 19:10:13  
 User Name: Jesse Saastamoinen  
 Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
 Test End: 05-joulu-2014 19:11:28  
 Manager:

**Curve check  $DI \geq 20\%$ , Slope1=50%, Bias=2, Slope2=100%, Dd0****Test Module**

Name: OMICRON Diff Operating Characteristic  
 Test Start: 05-joulu-2014 19:12:49  
 User Name: Jesse Saastamoinen  
 Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
 Test End: 05-joulu-2014 19:12:49  
 Manager:

**Test Results for Fault Type L1-L2-L3 at Reference Side Primary**

Idiff	Ibias	Nominal Trip Time	Actual Trip Time	State	Result
0,19 In	0,33 In	N/T	N/T	Tested	Passed
0,39 In	0,90 In	N/T	N/T	Tested	Passed
0,97 In	2,05 In	N/T	N/T	Tested	Passed
3,90 In	5,05 In	N/T	N/T	Tested	Passed
4,10 In	5,05 In	0,0400 s	0,0357 s	Tested	Passed
1,03 In	2,05 In	0,0400 s	0,0479 s	Tested	Passed
0,41 In	0,90 In	0,0400 s	0,0522 s	Tested	Passed
0,21 In	0,33 In	0,0400 s	0,0484 s	Tested	Passed

**Test State:****Test passed**

8 out of 8 points tested.

8 points passed.

0 points failed.

**Curve check (compensation) Dd0****Test Module**

Name:	OMICRON Diff Operating Characteristic	Version:	3.00 SR 2
Test Start:	05-joulu-2014 19:14:11	Test End:	05-joulu-2014 19:14:34
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

## Test Results for Fault Type L1-E at Reference Side Primary

Idiff	Ibias	Nominal Trip Time	Actual Trip Time	State	Result
0,24 In	0,60 In	N/T	0,1042 s	Tested	Failed
0,39 In	1,00 In	N/T	N/T	Tested	Passed
0,97 In	2,20 In	N/T	N/T	Tested	Passed
1,95 In	4,10 In	N/T	N/T	Tested	Passed
3,90 In	6,10 In	N/T	N/T	Tested	Passed
4,10 In	6,10 In	0,0400 s	N/T	Tested	Failed
2,05 In	4,10 In	0,0400 s	N/T	Tested	Failed
1,03 In	2,20 In	0,0400 s	N/T	Tested	Failed
0,41 In	1,00 In	0,0400 s	N/T	Tested	Failed
0,26 In	0,60 In	0,0400 s	0,0523 s	Tested	Passed

### Test State:

Test failed

10 out of 10 points tested.

5 points passed.

5 points failed.

## Test Object - Device Settings

### Substation/Bay:

Substation:

Bay:

Substation address:

Bay address:

### Device:

Name/description: CT="1A", CT'="1A"

Device type:

Serial/model number:

Additional info 1:

Additional info 2:

Manufacturer:

Device address:

## Vampset: Disable stages

### Test State:

Command executed

Test passed

### Test Module

Name:	OMICRON ExeCute
Test Start:	05-joulu-2014 19:15:53
User Name:	Jesse Saastamoinen
Company:	Schneider Electric - Vamp

Version:	3.00 SR 2
Test End:	05-joulu-2014 19:16:10
Manager:	

## Vampset: 87

### Test State:

Command executed

Test passed

### Test Module

Name:	OMICRON ExeCute
Test Start:	05-joulu-2014 19:17:29
User Name:	Jesse Saastamoinen
Company:	Schneider Electric - Vamp

Version:	3.00 SR 2
Test End:	05-joulu-2014 19:18:44
Manager:	

## Test Module

Name: OMICRON Diff Operating Version: 3.00 SR 2  
Characteristic  
Test Start: 05-joulu-2014 19:20:06 Test End: 05-joulu-2014 19:20:06  
User Name: Jesse Saastamoinen Manager:  
Company: Schneider Electric - Vamp

## Test Results for Fault Type L1-L2-L3 at Reference Side Primary

Idiff	Ibias	Nominal Trip Time	Actual Trip Time	State	Result
0,19 In	0,33 In	N/T	N/T	Tested	Passed
0,39 In	0,90 In	N/T	N/T	Tested	Passed
0,97 In	2,05 In	N/T	N/T	Tested	Passed
3,90 In	5,05 In	N/T	N/T	Tested	Passed
4,10 In	5,05 In	0,0400 s	0,0354 s	Tested	Passed
1,03 In	2,05 In	0,0400 s	0,0529 s	Tested	Passed
0,41 In	0,90 In	0,0400 s	0,0551 s	Tested	Passed
0,21 In	0,33 In	0,0400 s	0,0532 s	Tested	Passed

### Test State:

Test passed

8 out of 8 points tested.

8 points passed.

0 points failed.

## Curve check (compensation) Dd6

## Test Module

Name: OMICRON Diff Operating Version: 3.00 SR 2  
Characteristic  
Test Start: 05-joulu-2014 19:21:28 Test End: 05-joulu-2014 19:21:39  
User Name: Jesse Saastamoinen Manager:  
Company: Schneider Electric - Vamp

## Test Results for Fault Type L1-E at Reference Side Primary

Idiff	Ibias	Nominal Trip Time	Actual Trip Time	State	Result
0,24 In	0,60 In	N/T	N/T	Tested	Passed
0,39 In	1,00 In	N/T	N/T	Tested	Passed
0,97 In	2,20 In	N/T	N/T	Tested	Passed
1,95 In	4,10 In	N/T	N/T	Tested	Passed
3,90 In	6,10 In	N/T	N/T	Tested	Passed
4,10 In	6,10 In	0,0400 s	N/T	Tested	Failed
2,05 In	4,10 In	0,0400 s	N/T	Tested	Failed
1,03 In	2,20 In	0,0400 s	N/T	Tested	Failed
0,41 In	1,00 In	0,0400 s	N/T	Tested	Failed
0,26 In	0,60 In	0,0400 s	0,0542 s	Tested	Passed

### Test State:

Test failed

10 out of 10 points tested.

6 points passed.

4 points failed.

----- Group end: Pri/Sec = 5A/5A -----

----- Group end: Transformer differential stage DI> and DI>> (87) -----

## Test Object - Device Settings

### Substation/Bay:

Substation:  
Bay:

Substation address:  
Bay address:

### Device:

Name/description: CT=5A Mot.Nom.=4A  
Device type:  
Serial/model number:  
Additional info 1:  
Additional info 2:

Manufacturer:  
Device address:

## Vampset: Disable stages

### Test State:

Command executed  
Test passed

### Test Module

Name: OMICRON ExeCute  
Test Start: 05-joulu-2014 19:22:58  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
Test End: 05-joulu-2014 19:23:15  
Manager:

## Vampset: 51F2

### Test State:

Command executed  
Test passed

### Test Module

Name: OMICRON ExeCute  
Test Start: 05-joulu-2014 19:24:34  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
Test End: 05-joulu-2014 19:26:13  
Manager:

## Test Settings

### General

No. of ramp states: 1  
Total steps per test: 64  
Total time per test: 6,400  
No. of test executions: 1

Input Mode: Direct  
Fault Type:

### Ramped Quantities

I 1 / Magnitude  
I 1(+) / Magnitude

### Ramp States

Ramp	Ramp 1
I 1	<u>200,0 mA</u> 0,00 ° 100,00 Hz
I 1(+)	<u>4,000 A</u> 67,50 ° 50,000 Hz
Force abs. Phases	Yes
Sig 1 From	200,0 mA
Sig 1 To	480,0 mA
Sig 1 Delta	4,500 mA
Sig 1 d/dt	45,00 mA/s

<b>Sig 2 From</b>	4,000 A
<b>Sig 2 To</b>	4,000 A
<b>Sig 2 Delta</b>	0,000 A
<b>Sig 2 d/dt</b>	0,000 A/s
<b>DI1</b>	0
<b>dt per Step</b>	100,0 ms
<b>Ramp Steps</b>	64
<b>Ramp Time</b>	6,400s
<b>Trigger</b>	Bin
<b>Trigger Logic</b>	OR
<b>Start (A1)</b>	1
<b>Step back</b>	No
<b>Delay Time</b>	0,000 s

## Test Module

Name: OMICRON Ramping  
 Test Start: 05-joulu-2014 19:27:35  
 User Name: Jesse Saastamoinen  
 Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
 Test End: 05-joulu-2014 19:27:35  
 Manager:

## Test Results

### Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 1	Start (A1) 0->1	I 1	400,0 mA	398,0 mA	36,00 mA	36,00 mA	-2,000 mA	+	42,00

Assess: + .. Passed x .. Failed o .. Not assessed

### Test State:

Test passed

## Test Settings

### General

No. of ramp states: 1  
 Total steps per test: 64  
 Total time per test: 6,400  
 No. of test executions: 1

Input Mode: Direct  
 Fault Type:

### Ramped Quantities

I 2 / Magnitude  
 I 2(+) / Magnitude

### Ramp States

Ramp	Ramp 1
I 2	<u>200,0 mA</u> -120,00 ° 100,00 Hz
I 2(+)	<u>4,000 A</u> -142,50 ° 50,000 Hz
<b>Force abs. Phases</b>	Yes
<b>Sig 1 From</b>	200,0 mA
<b>Sig 1 To</b>	480,0 mA
<b>Sig 1 Delta</b>	4,500 mA
<b>Sig 1 d/dt</b>	45,00 mA/s
<b>Sig 2 From</b>	4,000 A
<b>Sig 2 To</b>	4,000 A
<b>Sig 2 Delta</b>	0,000 A
<b>Sig 2 d/dt</b>	0,000 A/s



DI1	0
dt per Step	100,0 ms
Ramp Steps	64
Ramp Time	6,400s
Trigger	Bin
Trigger Logic	OR
Start (A1)	1
Step back	No
Delay Time	0,000 s

## Test Module

Name: OMICRON Ramping  
 Test Start: 05-joulu-2014 19:28:56  
 User Name: Jesse Saastamoinen  
 Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
 Test End: 05-joulu-2014 19:28:57  
 Manager:

## Test Results

### Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 1	Start (A1) 0->1	I 2	400,0 mA	398,0 mA	36,00 mA	36,00 mA	-2,000 mA	+	41,30

Assess: + .. Passed x .. Failed o .. Not assessed

### Test State:

Test passed

## Test Settings

### General

No. of ramp states: 1  
 Total steps per test: 64  
 Total time per test: 6,400  
 No. of test executions: 1

Input Mode: Direct  
 Fault Type:

### Ramped Quantities

I 3 / Magnitude  
 I 3(+) / Magnitude

### Ramp States

Ramp	Ramp 1
I 3	<u>200,0 mA</u> 120,00 ° 100,00 Hz
I 3(+)	<u>4,000 A</u> -22,50 ° 50,000 Hz
Force abs. Phases	Yes
Sig 1 From	200,0 mA
Sig 1 To	480,0 mA
Sig 1 Delta	4,500 mA
Sig 1 d/dt	45,00 mA/s
Sig 2 From	4,000 A
Sig 2 To	4,000 A
Sig 2 Delta	0,000 A
Sig 2 d/dt	0,000 A/s
DI1	0
dt per Step	100,0 ms
Ramp Steps	64
Ramp Time	6,400s

Trigger	Bin
Trigger Logic	OR
Start (A1)	1
Step back	No
Delay Time	0,000 s

## Test Module

Name: OMICRON Ramping  
Test Start: 05-joulu-2014 19:30:18  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
Test End: 05-joulu-2014 19:30:18  
Manager:

## Test Results

### Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 1	Start (A1) 0->1	I 3	400,0 mA	402,5 mA	36,00 mA	36,00 mA	2,500 mA	+	53,70

Assess: + .. Passed x .. Failed o .. Not assessed

**Test State:**  
**Test passed**

## Vampset: Disable stages

**Test State:**  
**Command executed**  
**Test passed**

## Test Module

Name: OMICRON ExeCute  
Test Start: 05-joulu-2014 19:31:38  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
Test End: 05-joulu-2014 19:31:54  
Manager:

## Vampset: 51F2

**Test State:**  
**Command executed**  
**Test passed**

## Test Module

Name: OMICRON ExeCute  
Test Start: 05-joulu-2014 19:33:14  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
Test End: 05-joulu-2014 19:34:53  
Manager:

## Test Settings

### General

No. of ramp states: 2  
Total steps per test: 109  
Total time per test: 11,800  
No. of test executions: 1

Input Mode: Direct  
Fault Type:

## Ramped Quantities

I 1 / Magnitude  
I 1(+) / Magnitude

## Ramp States

Ramp	Ramp 1	Ramp 2
I 1	3,760 A 0,00 ° 100,00 Hz	3,760 A 0,00 ° 100,00 Hz
I 1(+)	4,000 A 67,50 ° 50,000 Hz	4,000 A 67,50 ° 50,000 Hz
Force abs. Phases	Yes	Yes
Sig 1 From	3,760 A	3,760 A
Sig 1 To	3,760 A	4,240 A
Sig 1 Delta	0,000 A	4,500 mA
Sig 1 d/dt	0,000 A/s	45,00 mA/s
Sig 2 From	4,000 A	4,000 A
Sig 2 To	4,000 A	4,000 A
Sig 2 Delta	0,000 A	0,000 A
Sig 2 d/dt	0,000 A/s	0,000 A/s
DI1	0	0
dt per Step	1,000 s	100,0 ms
Ramp Steps	1	108
Ramp Time	1,000s	10,800s
Trigger	None	Bin
Trigger Logic		OR
Start (A1)		1
Step back	No	No
Delay Time	0,000 s	0,000 s

## Test Module

Name: OMICRON Ramping  
Test Start: 05-joulu-2014 19:36:14  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
Test End: 05-joulu-2014 19:36:15  
Manager:

## Test Results

### Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 2	Start (A1) 0->1	I 1	4,000 A	4,008 A	36,00 mA	36,00 mA	7,500 mA	+	45,70

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:  
Test passed

## Test Settings

### General

No. of ramp states: 2  
Total steps per test: 109  
Total time per test: 11,800  
No. of test executions: 1

Input Mode: Direct  
Fault Type:

### Ramped Quantities

I 2 / Magnitude  
I 2(+) / Magnitude

## Ramp States

Ramp	Ramp 1	Ramp 2
I 2	<u>3,760 A</u> -120,00 ° 100,00 Hz	<u>3,760 A</u> -120,00 ° 100,00 Hz
I 2(+)	<u>4,000 A</u> -142,50 ° 50,000 Hz	<u>4,000 A</u> -142,50 ° 50,000 Hz
Force abs. Phases	Yes	Yes
Sig 1 From	3,760 A	3,760 A
Sig 1 To	3,760 A	4,240 A
Sig 1 Delta	0,000 A	4,500 mA
Sig 1 d/dt	0,000 A/s	45,00 mA/s
Sig 2 From	4,000 A	4,000 A
Sig 2 To	4,000 A	4,000 A
Sig 2 Delta	0,000 A	0,000 A
Sig 2 d/dt	0,000 A/s	0,000 A/s
DI1	0	0
dt per Step	1,000 s	100,0 ms
Ramp Steps	1	108
Ramp Time	1,000s	10,800s
Trigger	None	Bin
Trigger Logic		OR
Start (A1)		1
Step back	No	No
Delay Time	0,000 s	0,000 s

## Test Module

Name: OMICRON Ramping  
Test Start: 05-joulu-2014 19:37:36  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
Test End: 05-joulu-2014 19:37:37  
Manager:

## Test Results

### Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 2	Start (A1) 0->1	I 2	4,000 A	3,998 A	36,00 mA	36,00 mA	-1,500 mA	+	34,10

Assess: + .. Passed x .. Failed o .. Not assessed

### Test State:

Test passed

## Test Settings

### General

No. of ramp states: 2  
Total steps per test: 109  
Total time per test: 11,800  
No. of test executions: 1

Input Mode: Direct  
Fault Type:

### Ramped Quantities

I 3 / Magnitude  
I 3(+) / Magnitude

## Ramp States

Ramp	Ramp 1	Ramp 2
I 3	3,760 A 120,00 ° 100,00 Hz	3,760 A 120,00 ° 100,00 Hz
I 3(+)	4,000 A -22,50 ° 50,000 Hz	4,000 A -22,50 ° 50,000 Hz
Force abs. Phases	Yes	Yes
Sig 1 From	3,760 A	3,760 A
Sig 1 To	3,760 A	4,240 A
Sig 1 Delta	0,000 A	4,500 mA
Sig 1 d/dt	0,000 A/s	45,00 mA/s
Sig 2 From	4,000 A	4,000 A
Sig 2 To	4,000 A	4,000 A
Sig 2 Delta	0,000 A	0,000 A
Sig 2 d/dt	0,000 A/s	0,000 A/s
DI1	0	0
dt per Step	1,000 s	100,0 ms
Ramp Steps	1	108
Ramp Time	1,000s	10,800s
Trigger	None	Bin
Trigger Logic		OR
Start (A1)		1
Step back	No	No
Delay Time	0,000 s	0,000 s

## Test Module

Name: OMICRON Ramping  
 Test Start: 05-joulu-2014 19:38:58  
 User Name: Jesse Saastamoinen  
 Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
 Test End: 05-joulu-2014 19:38:58  
 Manager:

## Test Results

### Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 2	Start (A1) 0->1	I 3	4,000 A	4,016 A	36,00 mA	36,00 mA	16,50 mA	+	86,30

Assess: + .. Passed x .. Failed o .. Not assessed

### Test State:

Test passed

----- Group end:CT 5A-----  
 ----- Group end:Motor mode-----  
 ----- Group end:Second harmonic O/C stage If2> (51F2)-----  
 ----- Group:Fifth harmonic O/C stage If5> (51F5)-----  
 ----- Group:Motor mode-----  
 ----- Group:CT 5A-----

## Test Object - Device Settings

### Substation/Bay:

Substation:  
 Bay:

Substation address:  
 Bay address:

**Device:**

Name/description: CT=5A Mot.Nom.=4A  
Device type:  
Serial/model number:  
Additional info 1:  
Additional info 2:

Manufacturer:  
Device address:

**Vampset: Disable stages****Test State:**

Command executed

Test passed

**Test Module**

Name: OMICRON ExeCute  
Test Start: 05-joulu-2014 19:40:18  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
Test End: 05-joulu-2014 19:40:35  
Manager:

**Vampset: 51F5****Test State:**

Command executed

Test passed

**Test Module**

Name: OMICRON ExeCute  
Test Start: 05-joulu-2014 19:41:54  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
Test End: 05-joulu-2014 19:43:33  
Manager:

**Test Settings****General**

No. of ramp states: 2  
Total steps per test: 38  
Total time per test: 4,700  
No. of test executions: 1

Input Mode: Direct  
Fault Type:

**Ramped Quantities**

I 1 / Magnitude  
I 1(+) / Magnitude

**Ramp States**

Ramp	Ramp 1	Ramp 2
I 1	320,0 mA 0,00 ° 250,00 Hz	320,0 mA 0,00 ° 250,00 Hz
I 1(+)	4,000 A 67,50 ° 50,000 Hz	4,000 A 67,50 ° 50,000 Hz
Force abs. Phases	Yes	Yes
Sig 1 From	320,0 mA	320,0 mA
Sig 1 To	320,0 mA	480,0 mA
Sig 1 Delta	0,000 A	4,500 mA
Sig 1 d/dt	0,000 A/s	45,00 mA/s
Sig 2 From	4,000 A	4,000 A
Sig 2 To	4,000 A	4,000 A
Sig 2 Delta	0,000 A	0,000 A
Sig 2 d/dt	0,000 A/s	0,000 A/s
DI1	0	0
dt per Step	1,000 s	100,0 ms

Ramp Steps	1	37
Ramp Time	1,000s	3,700s
Trigger	None	Bin
Trigger Logic		OR
Start (A1)		1
Step back	No	No
Delay Time	0,000 s	0,000 s

## Test Module

Name: OMICRON Ramping  
 Test Start: 05-joulu-2014 19:44:54  
 User Name: Jesse Saastamoinen  
 Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
 Test End: 05-joulu-2014 19:44:55  
 Manager:

## Test Results

### Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 2	Start (A1) 0->1	I 1	400,0 mA	401,0 mA	76,00 mA	76,00 mA	1,000 mA	+	49,50

Assess: + .. Passed x .. Failed o .. Not assessed

### Test State:

Test passed

## Test Settings

### General

No. of ramp states: 2  
 Total steps per test: 38  
 Total time per test: 4,700  
 No. of test executions: 1

Input Mode: Direct  
 Fault Type:

### Ramped Quantities

I 2 / Magnitude  
 I 2(+) / Magnitude

### Ramp States

Ramp	Ramp 1	Ramp 2
I 2	320,0 mA -120,00 ° 250,00 Hz	320,0 mA -120,00 ° 250,00 Hz
I 2(+)	4,000 A -142,50 ° 50,000 Hz	4,000 A -142,50 ° 50,000 Hz
Force abs. Phases	Yes	Yes
Sig 1 From	320,0 mA	320,0 mA
Sig 1 To	320,0 mA	480,0 mA
Sig 1 Delta	0,000 A	4,500 mA
Sig 1 d/dt	0,000 A/s	45,00 mA/s
Sig 2 From	4,000 A	4,000 A
Sig 2 To	4,000 A	4,000 A
Sig 2 Delta	0,000 A	0,000 A
Sig 2 d/dt	0,000 A/s	0,000 A/s
DI1	0	0
dt per Step	1,000 s	100,0 ms
Ramp Steps	1	37
Ramp Time	1,000s	3,700s
Trigger	None	Bin
Trigger Logic		OR

Start (A1)		1
Step back	No	No
Delay Time	0,000 s	0,000 s

## Test Module

Name: OMICRON Ramping  
 Test Start: 05-joulu-2014 19:46:16  
 User Name: Jesse Saastamoinen  
 Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
 Test End: 05-joulu-2014 19:46:16  
 Manager:

## Test Results

### Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 2	Start (A1) 0->1	I 2	400,0 mA	401,0 mA	76,00 mA	76,00 mA	1,000 mA	+	45,20

Assess: + .. Passed x .. Failed o .. Not assessed

**Test State:**  
**Test passed**

## Test Settings

### General

No. of ramp states: 2  
 Total steps per test: 38  
 Total time per test: 4,700  
 No. of test executions: 1

Input Mode: Direct  
 Fault Type:

### Ramped Quantities

I 3 / Magnitude  
 I 3(+) / Magnitude

### Ramp States

Ramp	Ramp 1	Ramp 2
I 3	320,0 mA 120,00 ° 250,00 Hz	320,0 mA 120,00 ° 250,00 Hz
I 3(+)	4,000 A -22,50 ° 50,000 Hz	4,000 A -22,50 ° 50,000 Hz
Force abs. Phases	Yes	Yes
Sig 1 From	320,0 mA	320,0 mA
Sig 1 To	320,0 mA	480,0 mA
Sig 1 Delta	0,000 A	4,500 mA
Sig 1 d/dt	0,000 A/s	45,00 mA/s
Sig 2 From	4,000 A	4,000 A
Sig 2 To	4,000 A	4,000 A
Sig 2 Delta	0,000 A	0,000 A
Sig 2 d/dt	0,000 A/s	0,000 A/s
DI1	0	0
dt per Step	1,000 s	100,0 ms
Ramp Steps	1	37
Ramp Time	1,000s	3,700s
Trigger	None	Bin
Trigger Logic		OR
Start (A1)		1
Step back	No	No
Delay Time	0,000 s	0,000 s



## Test Module

Name: OMICRON Ramping  
Test Start: 05-joulu-2014 19:47:38  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
Test End: 05-joulu-2014 19:47:38  
Manager:

## Test Results

### Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 2	Start (A1) 0->1	I 3	400,0 mA	401,0 mA	76,00 mA	76,00 mA	1,000 mA	+	57,90

Assess: + .. Passed x .. Failed o .. Not assessed

**Test State:**  
**Test passed**

## Vampset: Disable stages

**Test State:**  
**Command executed**  
**Test passed**

## Test Module

Name: OMICRON ExeCute  
Test Start: 05-joulu-2014 19:48:58  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
Test End: 05-joulu-2014 19:49:15  
Manager:

## Vampset: 51F5

**Test State:**  
**Command executed**  
**Test passed**

## Test Module

Name: OMICRON ExeCute  
Test Start: 05-joulu-2014 19:50:34  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
Test End: 05-joulu-2014 19:52:13  
Manager:

## Test Settings

### General

No. of ramp states: 2  
Total steps per test: 109  
Total time per test: 11,800  
No. of test executions: 1

Input Mode: Direct  
Fault Type:

### Ramped Quantities

I 1 / Magnitude  
I 1(+) / Magnitude

## Ramp States

Ramp	Ramp 1	Ramp 2
I 1	3,760 A 0,00 ° 250,00 Hz	3,760 A 0,00 ° 250,00 Hz
I 1(+)	4,000 A 67,50 ° 50,000 Hz	4,000 A 67,50 ° 50,000 Hz
Force abs. Phases	Yes	Yes
Sig 1 From	3,760 A	3,760 A
Sig 1 To	3,760 A	4,240 A
Sig 1 Delta	0,000 A	4,500 mA
Sig 1 d/dt	0,000 A/s	45,00 mA/s
Sig 2 From	4,000 A	4,000 A
Sig 2 To	4,000 A	4,000 A
Sig 2 Delta	0,000 A	0,000 A
Sig 2 d/dt	0,000 A/s	0,000 A/s
DI1	0	0
dt per Step	1,000 s	100,0 ms
Ramp Steps	1	108
Ramp Time	1,000s	10,800s
Trigger	None	Bin
Trigger Logic		OR
Start (A1)		1
Step back	No	No
Delay Time	0,000 s	0,000 s

## Test Module

Name: OMICRON Ramping  
Test Start: 05-joulu-2014 19:53:35  
User Name: Jesse Saastamoinen  
Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
Test End: 05-joulu-2014 19:53:35  
Manager:

## Test Results

### Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 2	Start (A1) 0->1	I 1	4,000 A	3,994 A	76,00 mA	76,00 mA	-6,000 mA	+	41,20

Assess: + .. Passed x .. Failed o .. Not assessed

### Test State:

Test passed

## Test Settings

### General

No. of ramp states: 2  
Total steps per test: 109  
Total time per test: 11,800  
No. of test executions: 1

Input Mode: Direct  
Fault Type:

### Ramped Quantities

I 2 / Magnitude  
I 2(+) / Magnitude

## Ramp States

Ramp	Ramp 1	Ramp 2
I 2	<u>3,760 A</u> -120,00 ° 250,00 Hz	<u>3,760 A</u> -120,00 ° 250,00 Hz
I 2(+)	<u>4,000 A</u> -142,50 ° 50,000 Hz	<u>4,000 A</u> -142,50 ° 50,000 Hz
Force abs. Phases	Yes	Yes
Sig 1 From	3,760 A	3,760 A
Sig 1 To	3,760 A	4,240 A
Sig 1 Delta	0,000 A	4,500 mA
Sig 1 d/dt	0,000 A/s	45,00 mA/s
Sig 2 From	4,000 A	4,000 A
Sig 2 To	4,000 A	4,000 A
Sig 2 Delta	0,000 A	0,000 A
Sig 2 d/dt	0,000 A/s	0,000 A/s
DI1	0	0
dt per Step	1,000 s	100,0 ms
Ramp Steps	1	108
Ramp Time	1,000s	10,800s
Trigger	None	Bin
Trigger Logic		OR
Start (A1)		1
Step back	No	No
Delay Time	0,000 s	0,000 s

## Test Module

Name: OMICRON Ramping  
 Test Start: 05-joulu-2014 19:54:57  
 User Name: Jesse Saastamoinen  
 Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
 Test End: 05-joulu-2014 19:54:57  
 Manager:

## Test Results

### Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 2	Start (A1) 0->1	I 2	4,000 A	3,998 A	76,00 mA	76,00 mA	-1,500 mA	+	29,50

Assess: + .. Passed x .. Failed o .. Not assessed

### Test State:

Test passed

## Test Settings

### General

No. of ramp states: 2  
 Total steps per test: 109  
 Total time per test: 11,800  
 No. of test executions: 1

Input Mode: Direct  
 Fault Type:

### Ramped Quantities

I 3 / Magnitude  
 I 3(+) / Magnitude

## Ramp States

Ramp	Ramp 1	Ramp 2
I 3	<u>3,760 A</u> 120,00 ° 250,00 Hz	<u>3,760 A</u> 120,00 ° 250,00 Hz
I 3(+)	<u>4,000 A</u> -22,50 ° 50,000 Hz	<u>4,000 A</u> -22,50 ° 50,000 Hz
Force abs. Phases	Yes	Yes
Sig 1 From	3,760 A	3,760 A
Sig 1 To	3,760 A	4,240 A
Sig 1 Delta	0,000 A	4,500 mA
Sig 1 d/dt	0,000 A/s	45,00 mA/s
Sig 2 From	4,000 A	4,000 A
Sig 2 To	4,000 A	4,000 A
Sig 2 Delta	0,000 A	0,000 A
Sig 2 d/dt	0,000 A/s	0,000 A/s
DI1	0	0
dt per Step	1,000 s	100,0 ms
Ramp Steps	1	108
Ramp Time	1,000s	10,800s
Trigger	None	Bin
Trigger Logic		OR
Start (A1)		1
Step back	No	No
Delay Time	0,000 s	0,000 s

## Test Module

Name: OMICRON Ramping  
 Test Start: 05-joulu-2014 19:56:19  
 User Name: Jesse Saastamoinen  
 Company: Schneider Electric - Vamp

Version: 3.00 SR 2  
 Test End: 05-joulu-2014 19:56:19  
 Manager:

## Test Results

### Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 2	Start (A1) 0->1	I 3	4,000 A	3,998 A	76,00 mA	76,00 mA	-1,500 mA	+	61,20

Assess: + .. Passed x .. Failed o .. Not assessed

**Test State:**  
**Test passed**

----- Group end:CT 5A-----  
 ----- Group end:Motor mode-----  
 ----- Group end:Fifth harmonic O/C stage If5> (51F5)-----